RENESAS

RL78/I1C

RENESAS MCU

Datasheet

R01DS0281EJ0211 Rev.2.11 Nov 30, 2022

True Low Power Platform, Independent power supply RTC, Hardware AES, 32-bit MAC, 1.9 V to 5.5 V operation, 64 to 256 Kbyte Flash, for Electric AMI Power Meter Application

1. OUTLINE

1.1 Features

Target application

• Power meters

Ultra-low power consumption technology

- V_{DD} = single power supply voltage of 1.7 to 5.5 V^{Note 1}
- HALT mode
- STOP mode
- SNOOZE mode

RL78 CPU core

- CISC architecture with 3-stage pipeline
- Minimum instruction execution time: Can be changed from high speed (0.03125 µs: @ 32 MHz selection with PLL clock, 0.04167 µs: @ 24 MHz selection with high-speed on-chip oscillator) to ultra-low speed (66.6 µs: @ 15 kHz operation with low-speed on-chip oscillator)
- 16-bit multiplication, 16-bit multiply-accumulation, and 32-bit division are supported.
- Address space: 1 MB
- General-purpose registers: (8-bit register × 8) × 4 banks
- On-chip RAM: 6 KB to 16 KB

Code flash memory

- Code flash memory: 64 KB to 256 KB
- Block size: 1 KB
- Prohibition of block erase and rewriting (security function)
- On-chip debug function
- Self-programming (with boot swap function/flash shield window function)

Data flash memory

- Data flash memory: 2 KB
- Back ground operation (BGO): Instructions can be executed from the program memory while rewriting the data flash memory
- Number of rewrites: 1,000,000 times (TYP.)
- Voltage of rewrites: V_{DD} = 1.9 to 5.5 V

PLL clock^{Note 2}

• 32 MHz is selectable ($\Delta\Sigma$ A/D converter is operable even when the PLL clock is selected as a CPU clock.)

High-speed on-chip oscillator

- Select from 1 to 24 MHz (TYP.). However when it is used as a clock for the ΔΣ A/D converter, select from 24 MHz (TYP.), 12 MHz (TYP.), 6 MHz (TYP.), or 3 MHz (TYP.).
- High accuracy: ±1.0% (V_{DD} = 1.9 to 5.5 V, T_A = -20 to +85°C)
- On-chip high-speed on-chip oscillator clock frequency correction function

Middle-speed on-chip oscillator

 Select from 4 MHz/2 MHz/1 MHz (However ΔΣ A/D converter is disabled.)

Operating ambient temperature

• T_A = -40 to +85°C

Power management and reset function

- On-chip power-on-reset (POR) circuit for Internal VDD^{Note 3} power supply
- On-chip RTC power-on-reset (RTCPOR) circuit for VRTC power supply
- On-chip voltage detector (LVD) (Select interrupt and reset from 13 levels)

Voltage detective circuit

- Detective voltage for VDD pin (Select interrupt from 6 levels)
- Detective voltage for VBAT pin (Select interrupt from 7 levels)
- Detective voltage for VRTC pin (Select interrupt from 4 levels)
- Detective voltage for EXLVD pin (Select interrupt from 1 level)



Data transfer controller (DTC)

- Transfer mode: Normal mode, repeat mode, block
 mode
- Activation source: Start by interrupt sources
- Chain transfer function

Event link controller (ELC)

• Event signals of 22 types can be linked to the specified peripheral function.

On-chip 32-bit multiplier and multiply-accumulator

- 32 bits × 32 bits = 64 bits (Unsigned or signed)
- 32 bits × 32 bits + 64 bits = 64 bits (Unsigned or signed)

Serial interface

- Simplified SPI (CSI): 2 to 3 channels
- UART/UART (LIN-bus supported): 2 to 3 channels
- UART/IrDA: 1 channel
- Simplified I²C communication: 2 to 3 channels
- I²C communication: 1 channel

Timer

- 16-bit timer: 8 channels
- 12-bit interval timer: 1 channel
- 8-bit interval timer: 4 channels
- Independent power supply RTC: 1 channel (calendar for 99 years, alarm function, and clock correction function)
- Watchdog timer: 1 channel
- Oscillation stop detection circuit: 1 channel

LCD controller/driver

- Internal voltage boosting method, capacitor split method, and external resistance division method are switchable
- Segment signal output: 19 (15)^{Note 4} to 42 (38)^{Note 4}
- Common signal output: 4 (8)Note 4

A/D converter

- 24-Bit $\Delta\Sigma$ A/D converter: 3 or 4 channels
- 8/10-bit resolution A/D converter
 (V_{DD} = 1.9 to 5.5 V): 4 or 6 channels
- Internal reference voltage (1.45 V) and temperature sensor

I/O port

- I/O port: 35 to 68 (N-ch open drain I/O [6 V tolerance]: 3, N-ch open drain I/O [V_{DD} tolerance^{Note 5}/EV_{DD} tolerance⁶]: 10 to 16)
- Can be set to N-ch open drain, TTL input buffer, and on-chip pull-up resistor
- Different potential interface: Can connect to a 1.8/2.5/3 V device
- On-chip clock output/buzzer output controller
- On-chip key interrupt function

AES circuit^{Note 7}

- Cipher modes of operation: GCM/ECB/CBC
- Encryption key length: 128/192/256 bits

Others

- On-chip BCD (binary-coded decimal) correction circuit
- On-chip battery backup function
- **Notes 1.** The minimum operating voltage of this product varies according to the VBATEN setting value.

When VBATEN = 0, the minimum operating voltage is 1.7 V.

When VBATEN = 1, the minimum

operating voltage is 1.9 V.

As well, the minimum operating voltage of VRTC is 1.6 V.

- 2. R5F10NPJ, R5F10NMJ, R5F10NPG only.
- **3.** Either V_{DD} or VBAT is selected by the battery backup function.
- **4.** The values in parentheses are the number of signal outputs when 8 com is used.
- 5. 64 pin products only
- 6. 80 pin, 100 pin products only
- 7. Only available in R5F10N products.
- Remark The functions mounted depend on the product. See 1.6 Outline of Functions.



O ROM, RAM capacities

Code Flash	Data Flash	RAM	AES Function		RL78/I1C	
				64 pins	80 pins	100 pins
256 KB	2 KB	16 KB ^{Note 1}	Mounted	-	R5F10NMJ	R5F10NPJ
128 KB	2 KB	8 KB ^{Note 2}	Mounted	R5F10NLG	R5F10NMG	R5F10NPG
			Not mounted	R5F11TLG	-	-
64 KB	2 KB	6 KB	Mounted	R5F10NLE	R5F10NME	-
			Not mounted	R5F11TLE	-	-

- Notes 1. This is about 15 KB when the self-programming function is used. (For details, refer to CHAPTER 3 in the RL78/I1C User's Manual.)
 - 2. This is about 7 KB when the self-programming function is used (excluding in the case of the R5F10NPG). (For details, refer to CHAPTER 3 in the RL78/I1C User's Manual.)



1.2 List of Part Numbers

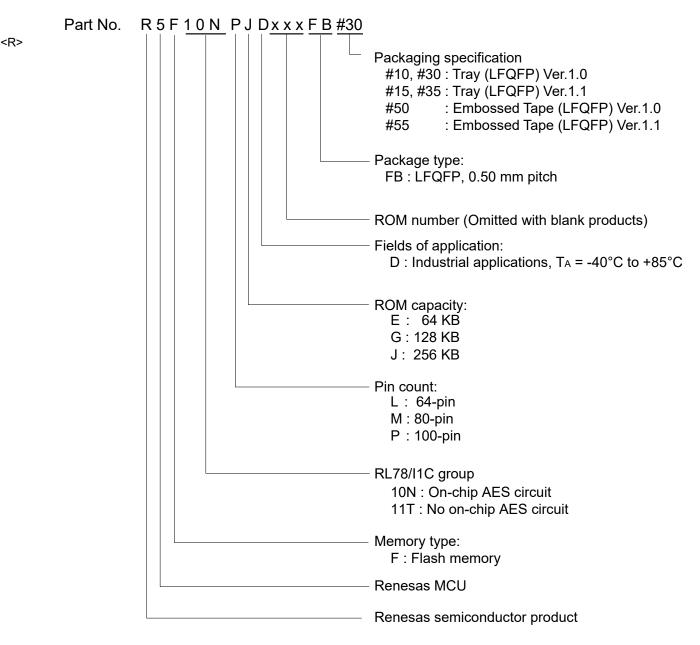


Figure 1-1. Part Number, Memory Size, and Package of RL78/I1C



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Table 1-1. List of Ordering Part Numbers

Pin Count	Package	Data Flash	AES Function	Fields of Application ^{Note}	Ordering Part Number
64 pins	64-pin plastic LFQFP	Mounted	Mounted	D	R5F10NLEDFB#10, R5F10NLGDFB#10,
	(10 × 10 mm, 0.5 mm				R5F10NLEDFB#15, R5F10NLGDFB#15,
	pitch)				R5F10NLEDFB#30, R5F10NLGDFB#30,
					R5F10NLEDFB#50, R5F10NLGDFB#50,
					R5F10NLEDFB#35, R5F10NLGDFB#35,
					R5F10NLEDFB#55, R5F10NLGDFB#55
			Not mounted	D	R5F11TLEDFB#10, R5F11TLGDFB#10,
					R5F11TLEDFB#15, R5F11TLGDFB#15,
					R5F11TLEDFB#30, R5F11TLGDFB#30,
					R5F11TLEDFB#50, R5F11TLGDFB#50,
					R5F11TLEDFB#35, R5F11TLGDFB#35,
					R5F11TLEDFB#55, R5F11TLGDFB#55
80 pins	80-pin plastic LFQFP	Mounted	Mounted	D	R5F10NMEDFB#10, R5F10NMGDFB#10,
	(12 × 12 mm, 0.5 mm				R5F10NMJDFB#10, R5F10NMEDFB#15,
	pitch)				R5F10NMGDFB#15, R5F10NMJDFB#15,
					R5F10NMEDFB#30, R5F10NMGDFB#30,
					R5F10NMJDFB#30, R5F10NMEDFB#35,
					R5F10NMGDFB#35, R5F10NMJDFB#35,
					R5F10NMEDFB#50, R5F10NMGDFB#50,
					R5F10NMJDFB#50, R5F10NMEDFB#55,
					R5F10NMGDFB#55, R5F10NMJDFB#55
100 pins	100-pin plastic LFQFP	Mounted	Mounted	D	R5F10NPJDFB#10, R5F10NPGDFB#10,
	(14 × 14 mm, 0.5 mm				R5F10NPJDFB#15, R5F10NPGDFB#15,
	pitch)				R5F10NPJDFB#30, R5F10NPGDFB#30,
					R5F10NPJDFB#35, R5F10NPGDFB#35,
					R5F10NPJDFB#50, R5F10NPGDFB#50,
					R5F10NPJDFB#55, R5F10NPGDFB#55

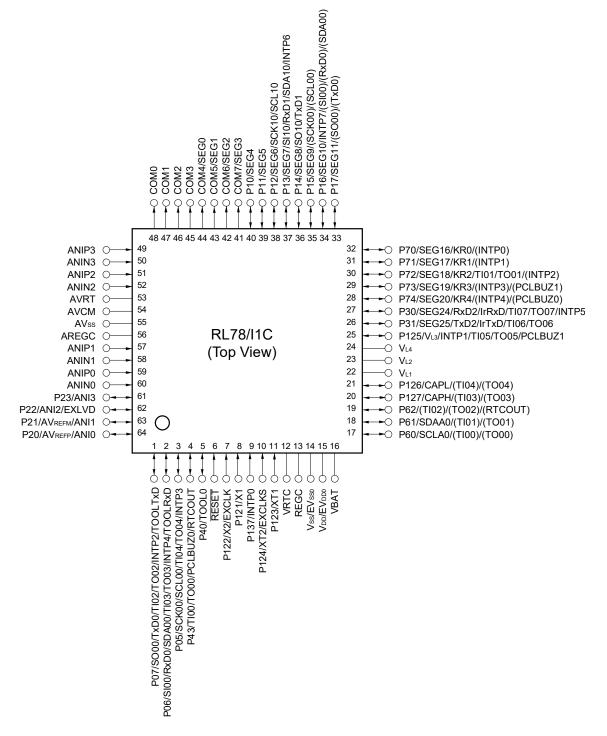
Note For the fields of application, see Figure 1-1 Part Number, Memory Size, and Package of RL78/I1C.

Caution The ordering part numbers represent the numbers at the time of publication. For the latest ordering part numbers, refer to the target product page of the Renesas Electronics website.

1.3 Pin Configuration (Top View)

1.3.1 64-pin products

• 64-pin plastic LFQFP (10 × 10 mm, 0.5 mm pitch)

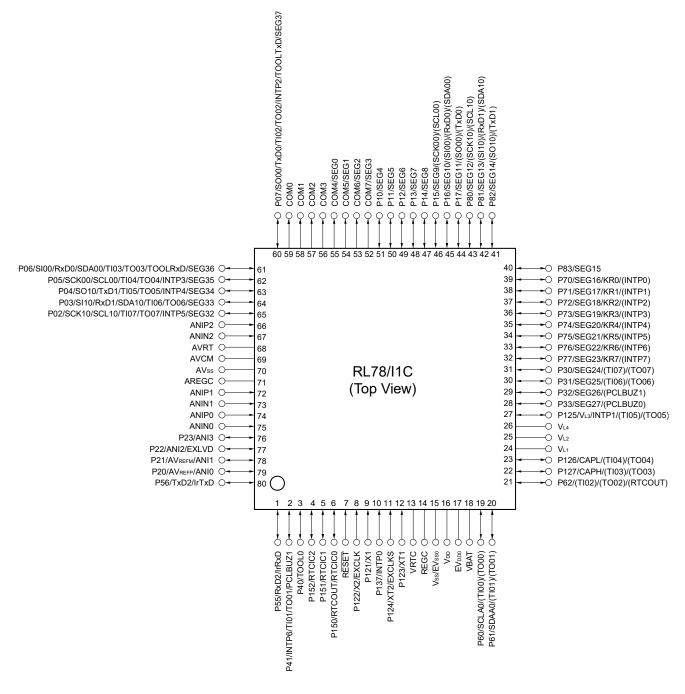


Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 $\mu F).$

- Remarks 1. For pin identification, see 1.4 Pin Identification.
 - Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.3.2 80-pin products

• 80-pin plastic LFQFP (12 × 12 mm, 0.5 mm pitch)



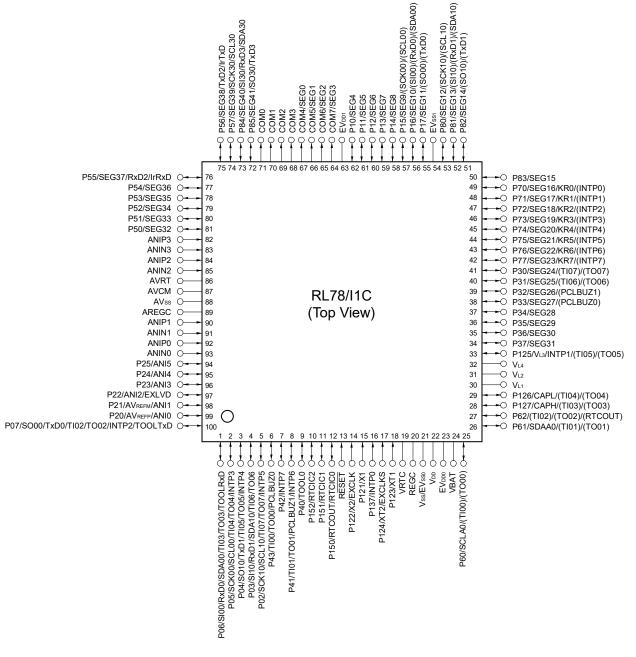
Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μ F).

Remarks 1. For pin identification, see 1.4 Pin Identification.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.3.3 100-pin products

• 100-pin plastic LFQFP (14 × 14 mm, 0.5 mm pitch)



Cautions 1. Make EVss1 the same potential as Vss/EVss0.

- 2. Make EVDD1 the same potential as EVDD0.
- 3. Connect the REGC pin to Vss via a capacitor (0.47 to 1 $\mu\text{F}).$
- Remarks 1. For pin identification, see 1.4 Pin Identification.
 - 2. When using the microcontroller for an application where the noise generated inside the microcontroller must be reduced, it is recommended to supply separate powers to the V_{DD} and EV_{DD1} pins and connect the Vss and EVss1 pins to separate ground lines.
 - 3. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

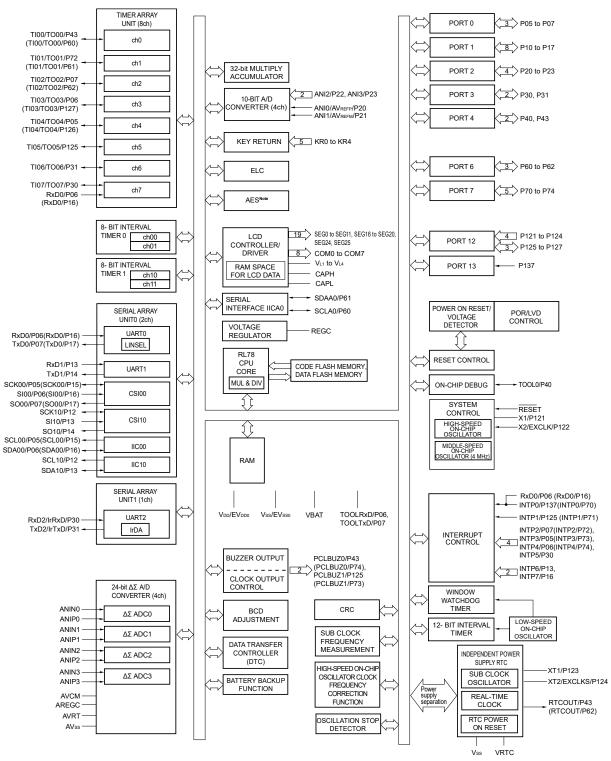
1.4 Pin Identification

ANI0 to ANI5:	Analog Input	P137:	Port 13
ANIN0 to ANIN3,		P150 to P152:	Port 15
ANIP0 to ANIP3:	Analog Input for $\Delta\Sigma$ ADC	PCLBUZ0,	
AREGC:	Regulator Capacitance for $\Delta\Sigma$ ADC	PCLBUZ1:	Programmable Clock Output/Buzzer
AVCM:	Control for ΔΣ ADC		Output
AVREFM:	A/D Converter Reference Potential	REGC:	Regulator Capacitance
	(– side) Input	RESET:	Reset
AVREFP:	A/D Converter Reference Potential (+ side) Input	RTCOUT:	Real-time Clock Correction Clock (1 Hz/64 Hz) Output
AVRT:	Reference Potential for $\Delta\Sigma$ ADC	RTCIC0 to RTCIC2	RTC Time Capture Event Input
AVss:	Ground for $\Delta\Sigma$ ADC	RxD0 to RxD3:	Receive Data for UART
CAPH, CAPL:	Capacitor Connection	SCL00, SCL10,	
0/ (i 11, 0/ (i E.	for LCD Controller/Driver	SCL30:	Serial Clock Output for Simplified IIC
COM0 to COM7:	Common Signal Output for LCD	SDA00, SDA10,	
	Controller/Driver	SDA30:	Serial Data Input/Output for Simplified IIC
EVDD0, EVDD1:	Power Supply for Port	SCLA0 :	Serial Clock Input/Output for IICA0
EVsso, EVss1:	Ground for Port	SDAA0:	Serial Data Input/Output for IICA0
EXCLK:	External Clock Input	SCK00, SCK10,	
	(Main System Clock)	SCK30:	Serial Clock Input/Output for CSI
EXCLKS:	External Clock Input	SEG0 to SEG41:	Segment Signal Output for LCD
	(Subsystem clock)		Controller/Driver
EXLVD:	External Input for Low Voltage	SI00, SI10, SI30:	Serial Data Input for CSI
	Detector		: Serial Data Output for CSI
INTP0 to INTP7:	Interrupt Request From Peripheral	TI00 to TI07:	Timer Input
IrRxD:	Receive Data for IrDA	TO00 to TO07:	Timer Output
IrTxD:	Transmit Data for IrDA	TOOL0:	Data Input/Output for Tool
KR0 to KR7:	Key Return	TOOLRxD,	
P02 to P07:	Port 0	TOOLTxD:	Data Input/Output for External Device
P10 to P17:	Port 1	TxD0 to TxD3:	Transmit Data for UART
P20 to P25:	Port 2	VBAT:	Battery Backup Power Supply
P30 to P37:	Port 3	Vdd:	Power Supply
P40 to P43:	Port 4	VL1 to VL4:	Voltage for Driving LCD
P50 to P57:	Port 5	VRTC:	RTC Power Supply
P60 to P62:	Port 6	Vss:	Ground
P70 to P77:	Port 7	X1, X2:	Crystal Oscillator (Main System
P80 to P85:	Port 8		Clock)
P121 to P127:	Port 12	XT1, XT2:	Crystal Oscillator (Subsystem Clock)



1.5 Block Diagram

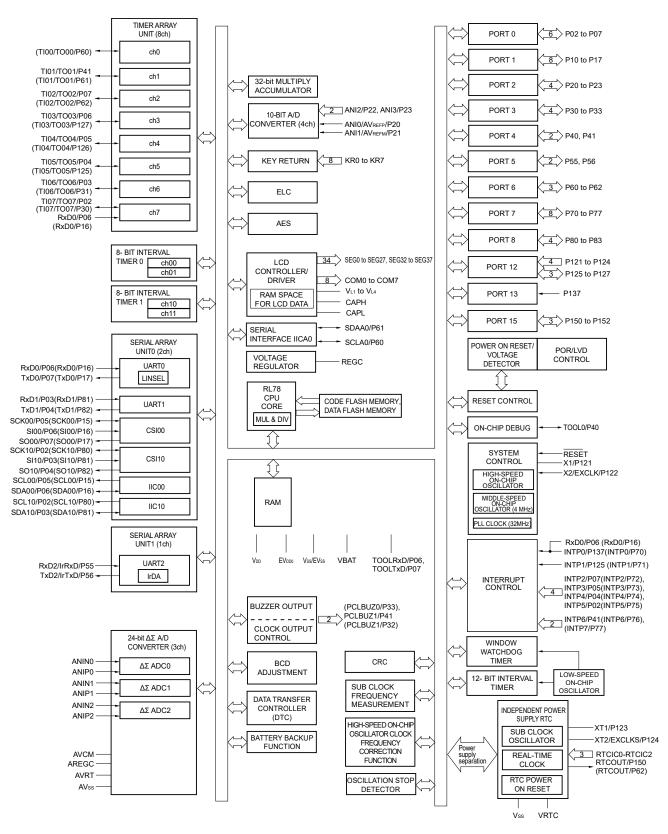
1.5.1 64-pin products



Note Only available in R5F10N products.

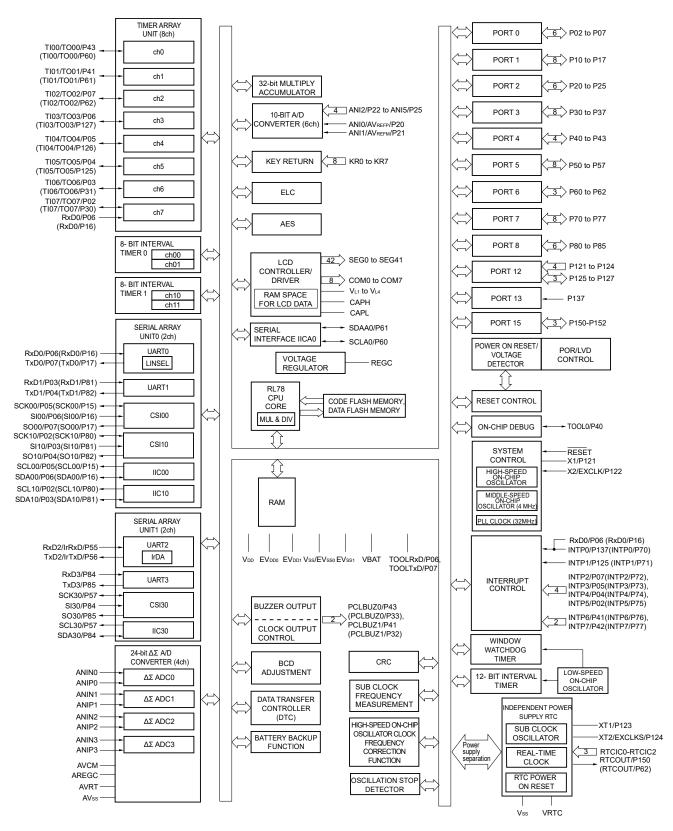
Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.5.2 80-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.5.3 100-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR0). See Figure 4-8 Format of Peripheral I/O Redirection Register (PIOR0) in the RL78/I1C User's Manual.

1.6 Outline of Functions

	Item	64-	·pin		80-pin		100	(1/3 -pin		
		R5F10NLEDFB/	R5F10NLGDFB/	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDFB		
		R5F11TLEDFB	R5F11TLGDFB							
Code flash m	emory (KB)	64 KB	128 KB	64 KB	128 KB	256 KB	128 KB	256 KB		
Data flash me					2 KB					
RAM (KB)	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	6 KB	8 KB ^{Note 1}	6 KB	8 KB ^{Note 1}	16 KB ^{Note 2}	8 KB	16 KB ^{Note 2}		
Address space	e	1 MB		I		I		I		
Main system clock	High-speed system clock High -speed on-chip oscillator clock (fiH) MAX.: 24 MHz Middle -speed on- chip oscillator clock	HS (High-spe HS (High-spe HS (High-spe HS (High-spe LS (Low-sper LV (Low-volta LP (Low-pow HS (High-spe HS (High-spe HS (High-spe LS (Low-sper LS (Low-volta	eed main) mod eed main) mod eed main) mod eed main) mod eed main) mod eer main) mod eed main) mod eed main) mod eed main) mod eed main) mod eed main) mod eage main) mod	ion, external m e: 1 to 20 MH: e: 1 to 16 MH: e: 1 to 12 MH: e: 1 to 6 MHz e: 1 to 6 MHz e: 1 to 8 MHz e: 1 to 4 MHz e: 1 to 24 MH: e: 1 to 24 MH: e: 1 to 12 MH: e: 1 to 6 MHz e: 1 to 8 MHz e: 1 to 8 MHz e: 1 to 4 MHz	$z (V_{DD} = 2.7 \text{ to} z (V_{DD} = 2.5 \text{ to} z (V_{DD} = 2.4 \text{ to} z (V_{DD} = 2.4 \text{ to} z (V_{DD} = 2.1 \text{ to} z (V_{DD} = 1.9 \text{ to} z z (V_{DD} = 1.9 \text{ to} z z (V_{DD} = 1.7 \text{ to} z z (V_{DD} = 2.7 \text{ to} z (V_{DD} = 2.5 \text{ to} z (V_{DD} = 2.4 \text{ to} z (V_{DD} = 2.1 \text{ to} z z (V_{DD} = 1.9 \text{ to} z z z z z z z z z z z z z z z z z z z$	5.5 V), 5.5 V),	ELK)			
	(fim)	LP (Low-pow	er main) mode	e: 1 MHz (Vod	= 1.9 to 5.5 V)				
	MAX.: 4 MHz					LIC (Llight on	and main) mad	a. 20 Miliz		
	PLL clock (fpll)			-		(V _{DD} = 2.8 to	n-speed main) mode: 32 MHz 8 to 5 5 V)			
Subsystem clock	Subsystem clock oscillator clock (fsx)		oscillation, ex TYP.): V _{DD} = 1	ternal subsyste .7 to 5.5 V	em clock input	(EXCLKS)				
	Low-speed on-chip oscillator clock (f⊾)	15 kHz (TYP	.): V _{DD} = 1.7 to	5.5V						
	n-chip oscillator clock rection function	Correct the fr	equency of the	e high-speed o	n-chip oscillato	or clock by the	subsystem clo	ock.		
General-purp	ose register	8 bits × 8 reg	isters × 4 banł	<s< td=""><td></td><td></td><td></td><td></td></s<>						
Minimum inst	ruction execution time	0.03125 µs (I	PLL clock: fpll	= 32 MHz sele	ection)					
		0.04167 µs (I	High-speed on	-chip oscillator	: f⊪ = 24 MHz	operation)				
		30.5 µs (Sub	system clock:	fsuв = 32.768 k	Hz operation)					
		66.6 μs (Low-speed on-chip oscillator: fιL = 15 kHz operation)								
Instruction se	t	Adder andMultiplicatiMultiplicati	on (16 bits × 1 on and accum	ical operation 6 bits), division ulation (16 bits pit manipulation	n (32 bits ÷ 32 s × 16 bits + 32	2 bits)	an operation), c	etc.		
I/O port	Total	3	5		52		(58		
	CMOS I/O	2	7		44		(50		
	CMOS input	į	5		5			5		
	CMOS output		-		-			-		
	N-ch O.D I/O (6 V tolerance)	:	3		3			3		

Notes 1. In the case of the 8 KB, this is about 7 KB when the self-programming function is used.

2. In the case of the 16 KB, this is about 15 KB when the self-programming function is used.

	Item	64-	pin		80-pin		100	-pin	
		R5F10NLEDFB/ R5F11TLEDFB	R5F10NLGDFB/ R5F11TLGDFB	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDFE	
Timer	16-bit timer TAU				8 channels		•		
	Watchdog timer	1 channel							
	12-bit interval timer	1 channel							
	8/16-bit interval timer			4 channels	(8-bit)/2 chani	nels (16-bit)			
	Independent power supply real-time clock (RTC)		1 channel						
	Oscillation stop				1 channel				
	detection circuit	-	<u> </u>						
	Timer output	Timer outputs							
	RTC output	1 channel ● 1 Hz/64 Hz	z (sub clock: fs	x = 32.768 kHz	<u>z</u>)				
	RTC time capture input		-			3 channels			
Clock out	tput/buzzer output				2				
		 256 Hz, 51 (Sub clock) 	2 Hz, 1.024 kH : fsx = 32.768 H	= 20 MHz ope Hz, 2.048 kHz, kHz operation)	4.096 kHz, 8.1	192 kHz, 16.38	84 kHz, 32.768		
10-bit res	solution A/D converter	4 cha	annels		4 channels		6 channels		
24-Bit ΔΣ	A/D Converter	4 channels 3 channels 4 channels					annels		
	SNDR	Typ. 80 dB (g Min. 69 dB (g Min. 65 dB (g	ain ×16)						
	Sampling frequency	3.906 kHz/1.9	,						
	PGA	×1, ×2, ×4, ×8	3, ×16, ×32						
Serial interface	Simplified SPI (CSI)/ UART/simplified I ² C:		annels		2 channels		3 cha	annels	
	UART/IrDA				1 channel				
	I ² C bus				1 channel				
32-bit mu	ultiplier and multiply-	32 bits × 32 b	oits = 64 bits (L	Insigned or sig	ned) (5 clock)				
accumula	ator	32 bits × 32 b	oits + 64 bits =	64 bits (Unsigi	ned or signed)	(5 clock)			
Data tran	nsfer controller (DTC)			36 sources			38 so	ources	
Event link	k Event input				9				
controller	r (ELC) Event trigger input				13				
LCD cont	troller/driver	Internal voltage		ethod, capacito	or split method	, and external	resistance divi	sion method	
	Segment signal output		5) ^{Note 2}		34 (30) ^{Note 2}		42 (3	8) ^{Note 2}	
	Common signal output				4 (8) ^{Note 2}				
				1	. /		1		
Vectored	Internal	4	1		41		4	4	

Notes 1. The number of outputs varies, depending on the setting of channels in use and the number of the master (see 8.9.3 Operation as multiple PWM output function in the RL78/I1C User's Manual).

2. The values in parentheses are the number of signal outputs when 8 com is used.

Item		64-	nin		80-pin		(3/3) 100-pin	
Rom		R5F10NLEDFB/	R5F10NLGDFB/	R5F10NMEDFB	R5F10NMGDFB	R5F10NMJDFB	R5F10NPGDFB	R5F10NPJDFB
		R5F11TLEDFB	R5F11TLGDFB					
Key interrupt input			5			8		
AES circuit ^{Note 3}		Cipher mode	s of operation:	GCM/ECB/CE	3C			
		-						
Reset	МСИ	 Reset by F Internal res Internal res Internal res Internal res Internal res Internal res 	 Internal reset by power-on-reset of internal V_{DD}^{Note 1} power supply Internal reset by voltage detector of internal V_{DD}^{Note 1} power supply 					
	RTC	RTC circui	t reset by RTC	Power-on-res	et			
Power-on-reset circuit	Internal VDD Note 1		reset: 1.51 \ vn-reset:1.50 \	· · ·				
	VRTC	RTC Powe RTC Powe	er-on-reset: er-down-reset:	1.52 V (TYP 1.50 V (TYP	,			
Voltage detector	Internal VDD Note 1	 Rising edge: 1.77 V to 4.06 V (13 stages) Falling edge: 1.73 V to 3.98 V (13 stages) 						
	Vdd		 Rising edge: 2.53 V to 3.77 V (6 stages) Falling edge: 2.46 V to 3.70 V (6 stages) 					
	VBAT		e: 2.11 V to 2. je: 2.05 V to 2.					
	VRTC		e: 2.22 V to 2. je: 2.16 V to 2.					
	EXLVD	Rising edgFalling edg						
Battery backup	CPU	VDD/VBAT						
function	ΔΣ A/D Converter	VDD/VBAT						
	RTC	VRTC (indep	endent power	supply)				
On-chip debug functior	1	Provided	pvided					
Power supply voltage		V _{DD} = 1.7 to 5	5.5 V					
Operating ambient tem	perature	$T_{A} = -40 \text{ to } +85^{\circ}\text{C}$						

Notes 1. Either VDD or VBAT is selected by the battery backup function.

2. This reset occurs when instruction code FFH is executed.

This reset does not occur during emulation using an in-circuit emulator or an on-chip debugging emulator.

3. Only available in R5F10N products.

2. ELECTRICAL SPECIFICATIONS

- Cautions 1. The RL78 microcontrollers have an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.
 - 2. The pins mounted depend on the product. See 2.1 Port Function to 2.2.1 With functions for each product in the RL78/I1C User's Manual.
- Remarks 1. In the descriptions in this chapter, read EVDD as EVDD0 and EVDD1, and EVSS as EVSS0 and EVSS1.
 - 2. For 64-pin products, read EV_{DD} as V_{DD} and EV_{SS} as V_{SS}.



2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	Vdd		-0.5 to +6.5	V
	EVDD		-0.5 to +6.5	V
	VBAT		-0.5 to +6.5	V
	VRTC		-0.5 to +6.5	V
REGC pin input voltage	VIREGC	REGC	-0.3 to +2.8 and -0.3 to $V_{\text{DD}}^{\text{Note 4}}$ +0.3 $^{\text{Note 1}}$	V
Input voltage	VI1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-0.3 to EV_DD +0.3 and -0.3 to V_DD Note 4 +0.3 Note 2	V
	V12	P60 to P62 (N-ch open-drain)	-0.3 to +6.5	V
	Vı3	P20 to P25, P121 to P122, P137, P150 to 152, EXCLK	–0.3 to $V_{DD}^{Note 4}$ +0.3 ^{Note 2}	V
	V ₁₄	RESET	-0.3 to +6.5	V
	V15	P123, P124, EXCLKS	-0.3 to VRTC +0.3 ^{Note 2}	V
Output voltage	V ₀₁	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	-0.3 to EV_{DD} +0.3 and -0.3 to V_{DD}^{Note 4} +0.3^{Note 2}	V
	V ₀₂	P20 to P25, P150 to P152	-0.3 to V _{DD} ^{Note 4} +0.3 ^{Note 2}	V
Analog input voltage	VAI1	ANI0 to ANI5	-0.3 to V_{DD}^{Note 4} +0.3 and -0.3 to AV_{REF(+)} +0.3^{Notes 2, 3}	V
	VAI2	ANIP0 to ANIP3, ANIN0 to ANIN3	-0.6 to +2.8 and -0.6 to AREGC +0.3 ^{Note 5}	V
Reference supply voltage	VIDSAD	AREGC, AVCM, AVRT	-0.3 to +2.8 and -0.3 to $V_{\text{DD}}^{\text{Note 4}}$ +0.3 $^{\text{Note 6}}$	V

Notes 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

- 2. Must be 6.5 V or lower.
- **3.** Do not exceed $AV_{REF(+)}$ + 0.3 V in case of A/D conversion target pin.
- 4. Either VDD or VBAT is selected by the battery backup function.
- 5. The $\Delta\Sigma$ A/D conversion target pin must not exceed AREGC +0.3 V.
- 6. Connect AREGC, AVCM, and AVRT terminals to Vss via capacitor (0.47 μF). This value defines the absolute maximum rating of AREGC, AVCM, and AVRT terminal. Do not use with voltage applied.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.
- **Remarks 1.** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.
 - 2. AV_{REF (+)}: + side reference voltage of the A/D converter.
 - **3.** Vss: Reference voltage

Absolute Maximum Ratings (2/3)

Parameter	Symbols		Conditions	Ratings	Unit
LCD voltage	VLI1	V₋ı voltage ^{Note 1}		–0.3 to 2.8 and –0.3 to V⊾4 +0.3	V
	VLI2	VL2 voltage ^{Note 1}		–0.3 to VL4 +0.3 ^{Note 2}	V
	VLI3	VL3 voltage ^{Note 1}		–0.3 to VL4 +0.3 ^{Note 2}	V
	VLI4	VL4 voltage ^{Note 1}		–0.3 to +6.5	V
	VLCAP	CAPL, CAPH vol	tage ^{Note 1}	–0.3 to VL4 +0.3 ^{Note 2}	V
	Vout	COM0 to COM7, SEG0 to SEG41,	External resistance division method	–0.3 to $V_{DD}^{Note 3}$ +0.3 ^{Note 2}	V
			Capacitor split method	–0.3 to $V_{DD}^{Note 3}$ +0.3 ^{Note 2}	V
			Internal voltage boosting method	–0.3 to VL4 +0.3 ^{Note 2}	V

Notes 1. This value only indicates the absolute maximum ratings when applying voltage to the V_{L1}, V_{L2}, V_{L3}, and V_{L4} pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47 μF ± 30%) and connect a capacitor (0.47 μF ± 30%) between the CAPL and CAPH pins.

- 2. Must be 6.5 V or lower.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.
- Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Vss: Reference voltage



Absolute Maximum Ratings (3/3)

Parameter	Symbols		Conditions	Ratings	Unit
Output current, high	Іон1	Per pin	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-40	mA
		Total of all pins	P02 to P07, P40 to P43	-70	mA
		–170 mA	P10 to P17, P30 to P37, P50 to P57, P70 to P77, P80 to P85, P125 to P127	-100	mA
	Іон2	Per pin	P20 to P25, P150 to P152	-0.5	mA
		Total of all pins		-2	mA
Output current, low	lol1	Per pin	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	40	mA
		Total of all pins 170 mA	P02 to P07, P40 to P43	70	mA
			P10 to P17, P30 to P37, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	100	mA
	IOL2	Per pin	P20 to P25, P150 to P152	1	mA
		Total of all pins		5	mA
Operating ambient	TA	In normal operati	on mode	-40 to +85	°C
temperature		In flash memory	programming mode		
Storage temperature	Tstg			-65 to +150	°C

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



2.2 Oscillator Characteristics

2.2.1 X1, XT1 oscillator characteristics

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le V_{DD}^{Note 2} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation	Ceramic resonator/	$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	1.0		20.0	MHz
frequency (fx) ^{Notes 1, 2}	crystal resonator	$2.5 \text{ V} \leq \text{V}_{\text{DD}} < 2.7 \text{ V}$	1.0		16.0	MHz
		$2.4 \text{ V} \leq \text{V}_{\text{DD}} < 2.5 \text{ V}$	1.0		12.0	MHz
		$1.9 \text{ V} \le \text{V}_{\text{DD}} < 2.4 \text{ V}$	1.0		8.0	MHz
		$1.7 \text{ V} \le \text{V}_{\text{DD}} < 1.9 \text{ V}$	1.0		4.0	MHz
XT1 clock oscillation frequency $(f_{XT})^{Notes 1, 2}$	Crystal resonator		32	32.768	35	kHz

Notes 1. Indicates only permissible oscillator frequency ranges. See **2.4 AC Characteristics** for instruction execution time. Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

- 2. Either VDD or VBAT is selected by the battery backup function.
- Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.
- Remark When using the X1 oscillator and XT1 oscillator, see 6.4 System Clock Oscillator in the RL78/I1C User's Manual.



2.2.2 On-chip oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{V}_{DD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{V}_{SS} = 0 \text{ V})$

Oscillators	Parameters		Conditions	MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency ^{Notes 1, 2}	fін			1.5		24	MHz
High-speed on-chip oscillator		–20 to +85°C	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 5.5 \text{ V}$	-1.0		+1.0	%
clock frequency accuracy			$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 1.9 \text{ V}$	-5.0		+5.0	%
		–40 to –20°C	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 5.5 \text{ V}$	-1.5		+1.5	%
			$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq 1.9 \text{ V}$	-5.5		+5.5	%
Middle-speed on-chip oscillator clock frequency ^{Note 2}	fім			1		4	MHz
Middle-speed on-chip oscillator clock frequency accuracy		$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 3}} \leq$	5.5 V	-12		+12	%
Low-speed on-chip oscillator clock frequency	fı∟				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

Notes 1. The high-speed on-chip oscillator frequency is selected by using bits 0 to 3 of option byte (000C2H/010C2H) and bits 0 to 2 of the HOCODIV register.

2. This indicates the oscillator characteristics only. See 2.4 AC Characteristics for the instruction execution time.

3. Either VDD or VBAT is selected by the battery backup function.



2.2.3 PLL oscillator characteristics

$(T_A = -40 \text{ to } +85^{\circ}C, 2.7 \text{ V} \le V_{DD}^{Note 2} \le 5.5 \text{ V}, \text{Vss} = 0 \text{ V})$

Oscillators	Parameters	Conditions	MIN.	TYP.	MAX.	Unit
PLL input frequency Note 1	fpllin	fін		4		MHz
PLL output frequency Note 1	fpll			32		MHz
Lockup wait time		Wait time from PLL output enable to frequency stabilization	40			μs
Interval wait time		Wait time from PLL stop to PLL restart setting	4			μs
Setting wait time		Wait time from PLL input clock stabilization and PLL setting fixedness to start-up setting	1			μs

Notes 1. Indicates only permissible oscillator frequency ranges.

2. Either VDD or VBAT is selected by the battery backup function.



2.3 DC Characteristics

2.3.1 Pin characteristics

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le EV_{DD0} = EV_{DD1} \le V_{DD}^{Note 4} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS0} = EV_{SS1} = 0 \text{ V})$

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, high ^{Note 1}	Іон1	Per pin for P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	$1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			-10.0 ^{Note 2}	mA
		Total of P02 to P07, P40 to P43	$4.0 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			-55.0	mA
		(When duty ≤ 70% ^{Note 3})	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			-10.0	mA
			1.9 V ≤ EV _{DD} < 2.7 V			-5.0	mA
			1.7 V ≤ EV _{DD} < 1.9 V			-2.5	mA
		Total of P10 to P17, P30 to P37, P50 to	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			-80.0	mA
		P57, P70 to P77, P80 to P85, P125 to P127 (When duty ≤ 70% ^{Note 3})	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			-19.0	mA
			$1.9 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$			-10.0	mA
			1.7 V ≤ EV _{DD} < 1.9 V			-5.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				-100.0	mA
	Іон2	Per pin for P20 to P25, P150 to P152	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 4}} \leq 5.5 \text{ V}$			-0.1 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 4}} \leq 5.5 \text{ V}$			-0.9	mA

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from the EV_{DD} and V_{DD} pins to an output pin.

2. Do not exceed the total current value.

3. Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = (Iон × 0.7)/(n × 0.01)

<Example> Where n = 80% and Ioн = -10.0 mA

Total output current of pins = $(-10.0 \times 0.7)/(80 \times 0.01) \approx -8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor.

A current higher than the absolute maximum rating must not flow into one pin.

4. Either V_{DD} or VBAT is selected by the battery backup function.

Caution P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output current, low ^{Note 1}	Iol1	Per pin for P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127				20.0 ^{Note 2}	mA
		Per pin for P60 to P62				15.0 ^{Note 2}	mA
		Total of P02 to P07, P40 to P43	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			70.0	mA
		(When duty ≤ 70% ^{Note 3})	$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}$			15.0	mA
			$1.9 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$			9.0	mA
			$1.7 \text{ V} \leq \text{EV}_{\text{DD}} < 1.9 \text{ V}$			4.5	mA
			$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			80.0	mA
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} < 4.0 \text{ V}$			35.0	mA
			$1.9 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$			20.0	mA
			$1.7 \text{ V} \leq \text{EV}_{\text{DD}} < 1.9 \text{ V}$			10.0	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})				150.0	mA
	lol2	Per pin for P20 to P25, P150 to P152	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 4}} \leq 5.5 \text{ V}$			0.4 ^{Note 2}	mA
		Total of all pins (When duty ≤ 70% ^{Note 3})	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 4}} \leq 5.5 \text{ V}$			3.6	mA

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD}0} = \text{EV}_{\text{DD}1} \le \text{V}_{\text{DD}}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS}0} = \text{EV}_{\text{SS}1} = 0 \text{ V})$

Notes 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the EVss and Vss pins.

- 2. However, do not exceed the total current value.
- **3.** Specification under conditions where the duty factor \leq 70%.

The output current value that has changed to the duty factor > 70% the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

• Total output current of pins = $(I_{OL} \times 0.7)/(n \times 0.01)$

<Example> Where n = 80% and IoL = 10.0 mA

Total output current of pins = $(10.0 \times 0.7)/(80 \times 0.01) \approx 8.7$ mA

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

- **4.** Either V_{DD} or VBAT is selected by the battery backup function.
- **Remark** Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	Vih1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Normal input buffer	0.8EVdd		EVDD	V
	VIH2	P02, P03, P05, P06, P12, P13, P15, P16, P30, P55, P57, P80, P81, P84	TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V	2.2		EVdd	V
			TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V	2.0		EVDD	V
			TTL input buffer 1.7 V ≤ EV _{DD} < 3.3 V	1.5		EVDD	V
	VIH3	P20 to P25		$0.7V_{\text{DD}}^{\text{Note}}$		V _{DD} ^{Note}	V
	VIH4	P60 to P62	0.7EV _{DD}		6.0	V	
	VIH5	P121 to P122, P137, P150 to P152, E	EXCLK	$0.8V_{\text{DD}}{}^{\text{Note}}$		V _{DD} ^{Note}	V
	VIH6	RESET	$0.8V_{\text{DD}}{}^{\text{Note}}$		6.0	V	
	VIH7	P123, P124, EXCLKS	0.8Vrtc		VRTC	V	
Input voltage, Iow	VIL1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Normal input buffer	0		0.2EV _{DD}	V
	VIL2	P02, P03, P05, P06, P12, P13, P15, P16, P30, P55, P57, P80, P81, P84	TTL input buffer 4.0 V ≤ EV _{DD} ≤ 5.5 V	0		0.8	V
			TTL input buffer 3.3 V ≤ EV _{DD} < 4.0 V	0		0.5	V
			TTL input buffer 1.7 V ≤ EV _{DD} < 3.3 V	0		0.32	V
	VIL3	P20 to P25		0		$0.3V_{\text{DD}}^{\text{Note}}$	V
	VIL4	P60 to P62		0		0.3EVDD	V
	VIL5	P121, P122, P137, P150 to P152, EX	CLK, RESET	0		$0.2V_{\text{DD}}^{\text{Note}}$	V
	VIL6	P123, P124, EXCLKS		0		0.2VRTC	V

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD}0} = \text{EV}_{\text{DD}1} \le \text{V}_{\text{DD}}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Note Either V_{DD} or VBAT is selected by the battery backup function.

Caution The maximum value of V_H of pins P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 is EV_{DD}, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Output voltage, high	Vон1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77,	,	EV _{DD} – 1.5			V
		P80 to P85, P125 to P127	4.0 V ≤ EV _{DD} ≤ 5.5 V, Іон1 = −3.0 mA	EV _{DD} – 0.7			V
			2.7 V ≤ EV _{DD} ≤ 5.5 V, Іон1 = –2.0 mA	EV _{DD} - 0.6			V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, Іон1 = −1.5 mA	EV _{DD} - 0.5			V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, Іон1 = −1.0 mA	EV _{DD} - 0.5			V
	Vон2	P20 to P25, P150 to P152	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note}} \leq 5.5 \text{ V},$ I _{OH2} = -100 µA	V _{DD} - 0.5			V
Output voltage, low	Vol1	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77,	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ Iol1 = 20 mA			1.3	V
		P80 to P85, P125 to P127	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ Iol1 = 8.5 mA			0.7	V
			$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V},$ Iol1 = 3.0 mA			0.6	V
			2.7 V ≤ EV _{DD} ≤ 5.5 V, Iol1 = 1.5 mA			0.4	V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, IoL1 = 0.6 mA			0.4	V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, IoL1 = 0.3 mA			0.4	V
	Vol2	P20 to P25, P150 to P152	1.7 V ≤ V _{DD} ^{Note} ≤ 5.5 V, I _{OL2} = 400 μA			0.4	V
	Vol3	P60 to P62	4.0 V ≤ EV _{DD} ≤ 5.5 V, IoL3 = 15.0 mA			2.0	V
			4.0 V ≤ EV _{DD} ≤ 5.5 V, IoL3 = 5.0 mA			0.4	V
			2.7 V ≤ EV _{DD} ≤ 5.5 V, IoL3 = 3.0 mA			0.4	V
			1.9 V ≤ EV _{DD} ≤ 5.5 V, IoL3 = 2.0 mA			0.4	V
			1.7 V ≤ EV _{DD} ≤ 5.5 V, Io∟3 = 1.0 mA			0.4	V

Note Either V_{DD} or VBAT is selected by the battery backup function.

Caution P02 to P07, P12 to P17, P31, P56, P57, P80 to P82, P84, and P85 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

Items	Symbol	Condit	MIN.	TYP.	MAX.	Unit			
Input leakage current, high	Ішні	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P60 to P62, P70 to P77, P80 to P85, P125 to P127	Vi = EV _{DD}				1	μA	
	Ilih2	P20 to P25, P137, P150 to P152, RESET	$V_I = V_{DD}^{Note}$				1	μA	
	Іцнз	P121, P122 (X1, X2, EXCLK)	$V_I = V_{DD}^{Note}$	In input port or external clock input			1	μA	
				In resonator connection			10	μA	
	Ilih4		P123, P124 (EXCLKS)	VI = VRTC	In input port or external clock input			1	μA
				In resonator connection			10	μA	
Input leakage current, low	Ilili	P02 to P07, P10 to P17, P30 to P37, P40 to P43, P50 to P57, P70 to P77, P80 to P85, P125 to P127	Vı = EVss			-1	μA		
	Ilil2	P20 to P25, P137, P150 to P152, RESET	VI = Vss			-1	μA		
	Ililis	P121, P122 (X1, X2, EXCLK)	VI = VSS	In input port or external clock input			-1	μA	
				In resonator connection			-10	μA	
	Ilil4	P123, P124 (EXCLKS)	VI = Vss	In input port or external clock input			-1	μA	
				In resonator connection			-10	μA	
On-chip pull-	Ru1	P10 to P17, P30 to P37, P50 to P57,	Vı = EVss	$2.4 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	10	20	100	kΩ	
up resistance		P70 to P77, P80 to P85, P125 to P127		$1.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	10	30	100	kΩ	
	Ru2	P02 to P07, P40 to P43, P150 to P152	VI = EVss		10	20	100	kΩ	

$(T_{A} = -40 \text{ to } +85^{\circ}\text{C})$	$1.7 V \leq EV_{DD0} = EV_{DD'}$	$1 \leq V_{DD}^{Note} \leq 5.5 V. Vss$	= EVsso = EVss1 = 0 V)

Note Either V_{DD} or VBAT is selected by the battery backup function.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.



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2.3.2 Supply current characteristics

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Parameter	Symbol	mbol		Conditions			MIN.	TYP.	MAX.	Unit
Supply		Operating	HS (high-	fclk = 32 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		5.2	8.5	mA
current ^{Note 1}		mode	speed main)	PLL operation	operation	V _{DD} = 3.0 V		5.2	8.5	mA
			mode ^{Note 5}	f⊪ = 24 MHz ^{Note 3}	Basic	V _{DD} = 5.0 V		1.7		mA
					operation	V _{DD} = 3.0 V		1.7		mA
					Normal	V _{DD} = 5.0 V		3.9	6.6	mA
					operation	V _{DD} = 3.0 V		3.9	6.6	mA
				f⊪ = 12 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		2.4	3.8	mA
				operation	V _{DD} = 3.0 V		2.4	3.8	mA	
				f⊪ = 6 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		1.7	2.6	mA
					operation	V _{DD} = 3.0 V		1.7	2.6	mA
			f⊪ = 3 MHz ^{Note 3}	Normal	V _{DD} = 5.0 V		1.3	2.0	mA	
					operation	V _{DD} = 3.0 V		1.3	2.0	mA
		LS (low-	f⊪ = 8 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		1.3	2.2	mA	
					operation	V _{DD} = 2.0 V		1.3	2.2	mA
					Normal	V _{DD} = 3.0 V		1.1	2.1	mA
					V _{DD} = 2.0 V		1.1	2.1	mA	
				f _{IH} = 4 MHz ^{Note 3} Normal	Normal	V _{DD} = 3.0 V		0.84	1.40	mA
					operation	V _{DD} = 2.0 V		0.84	1.40	mA
				f _{IM} = 4 MHz ^{Note 6}	Normal	V _{DD} = 3.0 V		0.70	1.20	mA
					operation	V _{DD} = 2.0 V		0.70	1.20	mA
				f⊪ = 3 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		0.7	1.4	mA
					operation	V _{DD} = 2.0 V		0.7	1.4	mA
			LV (low-	f⊪ = 4 MHz ^{Note 3}	Normal	V _{DD} = 3.0 V		1.3	1.9	mA
			voltage main) mode ^{Note 5}		operation	V _{DD} = 2.0 V		1.3	1.9	mA
			LP (low- power main) mode ^{Note 5}	f _{IH} = 1 MHz ^{Note 3} Normal operation	Normal	V _{DD} = 3.0 V		315	530	μA
					operation	V _{DD} = 2.0 V		315	530	μA
				fi⊨ = 1 MHz ^{Note 6}	Normal	V _{DD} = 3.0 V		160	300	μA
					operation	V _{DD} = 2.0 V		160	300	μA

(Notes and Remarks are listed on the page after the next page.)

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Parameter	Symbol		T	Conditions			MIN.	TYP.	MAX.	Unit
Supply	IDD1	Operating	HS (high-	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.3	5.5	mA
current ^{Note 1}		mode	speed main) mode ^{Note 5}	V _{DD} = 5.0 V	operation	Resonator connection		3.5	5.7	mA
			modente	f _{MX} = 20 MHz ^{Note 2} ,	Normal	Square wave input		3.3	5.5	m/
				V _{DD} = 3.0 V	operation	Resonator connection		3.5	5.7	m/
				f _{MX} = 16 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.4	m/
				V _{DD} = 5.0 V	operation	Resonator connection		2.9	4.6	m/
				f _{MX} = 16 MHz ^{Note 2} ,	Normal	Square wave input		2.8	4.4	m/
			V _{DD} = 3.0 V	operation	Resonator connection		2.9	4.6	m/	
			f _{MX} = 12 MHz ^{Note 2} ,	Normal	Square wave input		2.3	3.6	m/	
			V _{DD} = 5.0 V	operation	Resonator connection		2.4	3.7	m	
			f _{MX} = 12 MHz ^{Note 2} ,	Normal	Square wave input		2.3	3.6	m	
				V _{DD} = 3.0 V	operation	Resonator connection		2.4	3.7	m
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.0	3.2	m
				V _{DD} = 5.0 V	operation	Resonator connection		2.1	3.3	m
				f _{MX} = 10 MHz ^{Note 2} ,	Normal	Square wave input		2.0	3.2	m
				V _{DD} = 3.0 V	operation	Resonator connection		2.1	3.3	m
			LS (low- speed main) mode ^{Note 5}	f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	2.0	m
				V _{DD} = 3.0 V	operation	Resonator connection		1.2	2.1	m
				f _{MX} = 8 MHz ^{Note 2} ,	Normal	Square wave input		1.1	2.0	m
				V _{DD} = 2.0 V	operation	Resonator connection		1.2	2.1	m
				f _{MX} = 4 MHz ^{Note 2} ,	Normal	Square wave input		0.7	1.2	m
				V _{DD} = 3.0 V	operation	Resonator connection		0.7	1.3	m
				f _{MX} = 4 MHz ^{Note 2} ,	Normal	Square wave input		0.7	1.2	m
				$V_{DD} = 2.0 V$ operation R	Resonator connection		0.7	1.3	m	
			power main) modo ^{№te 5}	fı⊣ = 1 MHz ^{Note 2} ,	Normal	Square wave input		140	240	μA
				V _{DD} = 3.0 V	operation	Resonator connection		190	300	μA
				fı⊣ = 1 MHz ^{Note 2} ,	Normal	Square wave input		140	240	μA
				V _{DD} = 2.0 V	operation	Resonator connection		190	300	μA
				fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.1	6.6	μA
			operation	$T_A = -40^{\circ}C$	operation	Resonator connection		5.2	6.7	μA
				fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.4	7.1	μA
				T _A = +25°C	operation	Resonator connection		5.5	7.2	μA
				fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		5.6	8.0	μA
				T _A = +50°C	operation	Resonator connection		5.7	8.1	μA
				fsub = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		6.1	9.7	μA
				T _A = +70°C	operation	Resonator connection		6.2	9.8	μA
				fsuв = 32.768 kHz ^{Note 4} ,	Normal	Square wave input		6.8	13.7	μA
				T _A = +85°C	operation	Resonator connection		6.9	13.8	ι μ/
			fu T	fi∟ = 15 kHz,	Normal			2.5	7.0	μ/ μ/
				$T_A = +85^{\circ}C^{\text{Note 7}}$	operation			2.0		μ,
				f⊩ = 15 kHz,	Normal			2.8	7.0	μA
				$T_A = -40^{\circ}C^{\text{Note 7}}$	operation					
				fı∟ = 15 kHz,	Normal			4.1	11.0	μA
				T _A =+ 25°C ^{Note 7}	operation					

$(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le EV_{DD0} = EV_{DD1} \le V_{DD}^{Note 8} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS0} = EV_{SS1} = 0 \text{ V})$

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(Notes and Remarks are listed on the next page.)



- Notes 1. Total current flowing into VDD, EVDD, and VRTC including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or Vss, EVss. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, ΔΣ A/D converter, LVD circuit, battery backup circuit, I/O port, and on-chip pull-up/pull-down resistors. When the VBAT pin (pin for battery backup) is selected, current flowing into VBAT.
 - 2. When high-speed on-chip oscillator, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **3.** When high-speed system clock, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - 4. When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped. When setting ultra-low current consumption (AMPHS1 = 1). However, not including the current flowing into Independent power supply RTC, 12-bit interval timer, and watchdog timer.
 - Relationship between operation voltage width, operation frequency of CPU and operation mode is as below. HS (high-speed main) mode: 2.8 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 32 MHz
 - $2.7 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 24 \text{ MHz}$ $2.5 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 16 \text{ MHz}$ $2.4 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 12 \text{ MHz}$ $2.1 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 12 \text{ MHz}$ $2.1 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 6 \text{ MHz}$ $LS \text{ (low-speed main) mode:} \quad 1.9 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz to } 8 \text{ MHz}$ $LP \text{ (low-power main) mode:} \quad 1.9 \lor \leq \lor_{DD} \leq 5.5 \lor @1 \text{ MHz}$
 - LV (low-voltage main) mode: 1.7 V ≤ V_{DD} ≤ 5.5 V@1 MHz to 4 MHz
 - **6.** When high-speed on-chip oscillator, low-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped.
 - 7. When high-speed on-chip oscillator, middle-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped.
 - 8. Either VDD or VBAT is selected by the battery backup function.
- **Remarks 1.** fMX: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - 3. fim: Middle-speed on-chip oscillator clock frequency
 - 4. fiL: Low-speed on-chip oscillator clock frequency
 - 5. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 6. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C



Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	DD2 ^{Note 2}	HALT	HS (high-	fclk = 32 MHz ^{Note 4} ,	V _{DD} = 5.0 V		0.80	2.0	mA
current ^{Note 1}		mode	speed main)	PLL operation	V _{DD} = 3.0 V		0.80	2.0	mA
			mode ^{Note 7}	f⊪ = 24 MHz ^{Note 4}	V _{DD} = 5.0 V		0.48	1.45	mA
					V _{DD} = 3.0 V		0.48	1.45	mA
				f⊪ = 12 MHz ^{Note 4}	V _{DD} = 5.0 V		0.37	0.91	mA
					V _{DD} = 3.0 V		0.37	0.91	mA
			f⊪ = 6 MHz ^{Note 4}	V _{DD} = 5.0 V		0.32	0.63	mA	
				V _{DD} = 3.0 V		0.32	0.63	mA	
				f⊪ = 3 MHz ^{Note 4}	V _{DD} = 5.0 V		0.29	0.49	mA
					V _{DD} = 3.0 V		0.29	0.49	mA
			LS (low-	f⊪ = 8 MHz ^{Note 4}	V _{DD} = 3.0 V		280	740	μA
			speed main)		V _{DD} = 2.0 V		280	740	μA
			mode ^{Note 7}	f⊪ = 6 MHz ^{Note 4}	V _{DD} = 3.0 V		230	620	μA
				V _{DD} = 2.0 V		230	620	μA	
				f⊪ = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		220	440	μA
					V _{DD} = 2.0 V		220	440	μA
				fi⊨ = 4 MHz ^{Note 9}	V _{DD} = 3.0 V		55	300	μA
				V _{DD} = 2.0 V		55	300	μA	
			f⊮ = 3 MHz ^{Note 4}	V _{DD} = 3.0 V		200	534	μA	
				V _{DD} = 2.0 V		200	534	μA	
			LV (low-	f⊮ = 4 MHz ^{Note 4}	V _{DD} = 3.0 V		450	825	μA
			voltage main) mode ^{Note 7}		V _{DD} = 2.0 V		450	825	μA
			LP (low- power main)	f⊮ = 1 MHz ^{Note 4}	V _{DD} = 3.0 V		195	400	μA
					V _{DD} = 2.0 V		195	400	μA
			mode ^{Note 7}	f _{IM} = 1 MHz ^{Note 9}	V _{DD} = 3.0 V		33	100	μA
					V _{DD} = 2.0 V		33	100	μA
			HS (high-	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.31	1.08	mA
			speed main)	V _{DD} = 5.0 V	Resonator connection		0.48	1.28	mA
			mode ^{Note 7}	f _{MX} = 20 MHz ^{Note 3} ,	Square wave input		0.31	1.08	mA
				V _{DD} = 3.0 V	Resonator connection		0.48	1.28	mA
				f _{MX} = 16 MHz ^{Note 3} ,	Square wave input		0.28	0.86	mA
				V _{DD} = 5.0 V	Resonator connection		0.42	1.00	mA
				f _{MX} = 16 MHz ^{Note 3} ,	Square wave input		0.28	0.86	mA
				V _{DD} = 3.0 V	Resonator connection		0.42	1.00	mA
				f _{MX} = 12 MHz ^{Note 3} ,	Square wave input		0.23	0.70	mA
				V _{DD} = 5.0 V	Resonator connection		0.37	0.79	mA
			f _{MX} = 12 MHz ^{Note 3} ,	Square wave input		0.23	0.70	mA	
				V _{DD} = 3.0 V	Resonator connection		0.36	0.79	mA
				f _{MX} = 10 MHz ^{Note 3} ,	Square wave input		0.21	0.63	mA
				V _{DD} = 5.0 V	Resonator connection		0.29	0.71	mA
				$f_{MX} = 10 \text{ MHz}^{\text{Note 3}},$	Square wave input		0.21	0.63	mA
				V _{DD} = 3.0 V	Resonator connection		0.28	0.71	mA

	(T _A = -40 to +85°C, 1.7 V ≤ EV _{DD0} = EV _{DD1} ≤ V _{DD^{Note 10} ≤ 5.5 V, V_{SS} = EV_{SS0} = EV_{SS1} = 0 V)}	(3/6)
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(Notes and Remarks are listed on the page after the next page.)

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Parameter	Symbol			Conditions		MIN.	TYP.	MAX.	Unit
Supply	DD2Note 2	HALT	LS (low-	f _{MX} = 8 MHz ^{Note 3} ,	Square wave input		110	360	μA
current ^{Note 1}		mode	speed main)	V _{DD} = 3.0 V	Resonator connection		160	420	μA
			mode ^{Note 7}	f _{MX} = 8 MHz ^{Note 3} ,	Square wave input		110	360	μA
				V _{DD} = 2.0 V	Resonator connection		160	420	μA
				f _{MX} = 4 MHz ^{Note 3} ,	Square wave input		39	200	μA
				V _{DD} = 3.0 V	Resonator connection		81	250	μA
				$f_{MX} = 4 \text{ MHz}^{Note 3}$,	Square wave input		39	200	μA
				V _{DD} = 2.0 V	Resonator connection		81	250	μA
			LP (low-	f _{MX} = 1 MHz ^{Note 3} ,	Square wave input		14	100	μA
			power main)	V _{DD} = 3.0 V	Resonator connection		70	200	μA
			mode ^{Note 7}	f _{MX} = 1 MHz ^{Note 3} ,	Square wave input		14	100	μA
				V _{DD} = 2.0 V	Resonator connection		70	200	μA
			Subsystem	fsub = 32.768 kHz ^{Note 5} ,	Square wave input		0.80	1.60	μA
			clock	$T_A = -40^{\circ}C$	Resonator connection		1.00	1.80	μA
			operation	fsue = 32.768 kHz ^{Note 5} ,	Square wave input		0.93	1.70	μA
				T _A = +25°C	Resonator connection		1.13	1.90	μA
				f _{SUB} = 32.768 kHz ^{Note 5} , T _A = +50°C	Square wave input		1.10	3.00	μA
					Resonator connection		1.30	3.20	μA
				fsub = 32.768 kHz ^{Note 5} ,	Square wave input		1.50	5.00	μA
				T _A = +70°C	Resonator connection		1.70	5.20	μA
				fsue = 32.768 kHz ^{Note 5} ,	Square wave input		2.80	9.00	μA
				T _A = +85°C	Resonator connection		3.00	9.20	μA
				f⊩ = 15 kHz ^{Note 9} ,			0.78	1.60	μA
				$T_A = -40^{\circ}C$					μA
				f⊩ = 15 kHz ^{Note 9} ,			1.01	1.76	μA
				T _A = +25°C					μA
				f⊩ = 15 kHz ^{Note 9} ,			2.25	8.45	μA
				T _A = +85°C					μA
	IDD3 ^{Note 6}	STOP	T _A = -40°C				0.47	0.90	μA
		mode ^{Note 8}	T _A = +25°C				0.65	1.20	μA
			T _A = +50°C				0.84	2.80	μA
			T _A = +70°C				1.21	4.70	μA
			T _A = +85°C				1.82	9.00	μA

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD}0} = \text{EV}_{\text{DD}1} \le \text{V}_{\text{DD}}^{\text{Note } 10} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$ (4/6)

(Notes and $\ensuremath{\textit{Remarks}}$ are listed on the next page.)



- Notes 1. Total current flowing into VDD, EVDD, and VRTC including the input leakage current flowing when the level of the input pin is fixed to VDD, EVDD or VSS, EVSS. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, ΔΣ A/D converter, LVD circuit, battery backup circuit, I/O port, and on-chip pull-up/pull-down resistors. When the VBAT pin (pin for battery backup) is selected, current flowing into VBAT.
 - 2. During HALT instruction execution by flash memory.
 - **3.** When high-speed on-chip oscillator, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **4.** When high-speed system clock, middle-speed on-chip oscillator, low-speed on-chip oscillator, and subsystem clock are stopped.
 - **5.** When operating independent power supply RTC and setting ultra-low current consumption (AMPHS1 = 1). When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped. However, not including the current flowing into the 12-bit interval timer and watchdog timer.
 - **6.** When high-speed on-chip oscillator, high-speed system clock, and subsystem clock are stopped. However, not including the current flowing into independent power supply RTC, 12-bit interval timer, and watchdog timer.
 - 7. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: $2.8 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}@1 \text{ MHz}$ to 32 MHz

 $\begin{array}{l} 2.7 \ V \leq V_{DD} \leq 5.5 \ V@1 \ MHz \ to \ 24 \ MHz \\ 2.5 \ V \leq V_{DD} \leq 5.5 \ V@1 \ MHz \ to \ 16 \ MHz \\ 2.4 \ V \leq V_{DD} \leq 5.5 \ V@1 \ MHz \ to \ 12 \ MHz \\ 2.1 \ V \leq V_{DD} \leq 5.5 \ V@1 \ MHz \ to \ 6 \ MHz \end{array}$

- LS (low-speed main) mode: $1.9 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V} @1 \text{ MHz}$ to 8 MHz
- LP (low-power main) mode: $1.9 \text{ V} \le \text{V}_{DD} \le 5.5 \text{ V}@1 \text{ MHz}$
- LV (low-voltage main) mode: $1.7 \text{ V} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}@1 \text{ MHz}$ to 4 MHz
- **8.** If operation of the subsystem clock when STOP mode, same as when HALT mode of subsystem clock operation.
- 9. When high-speed on-chip oscillator, middle-speed on-chip oscillator, and high-speed system clock are stopped.
- **10.** Either VDD or VBAT is selected by the battery backup function.
- **Remarks 1.** f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)
 - 2. fin: High-speed on-chip oscillator clock frequency
 - **3.** fim: Middle-speed on-chip oscillator clock frequency
 - 4. fiL: Low-speed on-chip oscillator clock frequency
 - 5. fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - 6. Except subsystem clock operation and STOP mode, temperature condition of the TYP. value is TA = 25°C



•			$1 \leq V_{DD}^{Note \ 15} \leq 5.5 \text{ V}, \text{ Vss} = \text{EVsso}$				(5/6
Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Independent power supply RTC operating current	I _{RTC} Notes 3	fsuв = 32.768 kHz			0.70		μA
12-bit interval timer operating current	_{TMKA} Notes 1, 2, 4	fsuв = 32.768 kHz	fmain is stopped		0.04		μA
8-bit interval timer operating	_{TMT} Notes 1, 2, 5	fsuв = 32.768 kHz fмаin is stopped,	8-bit counter mode × 2 ch operation		0.12		μA
current		per unit	16-bit counter mode operation		0.10		μA
Watchdog timer operating current	WDT ^{Notes 1, 2, 6}	fil = 15 kHz, fmain	s stopped		0.22		μA
LVD operating current	I _{LVD} Notes 1, 7				0.10		μA
LVDVDD	ILVDVDD	Current flowing to	Vdd		0.05		μA
operating current		Current flowing to	VDD or VBAT ^{Note 1}		0.04		μA
LVDVBAT	ILVDVBAT	Current flowing to	VBAT		0.04		μA
operating current		Current flowing to	VDD or VBAT ^{Note 1}		0.04		μA
LVDVRTC	ILVDVRTC	Current flowing to	VRTC		0.04		μA
operating current		Current flowing to	VDD or VBAT ^{Note 1}		0.04		μA
LVDEXLVD	ILVDEXLVD	Current flowing to	EXLVD		0.16		μA
operating current		Current flowing to	VDD or VBAT ^{Note 1}		0.04		μA
Oscillation stop detection circuit operating current	IOSDC ^{Note 1}				0.02		μA
Battery backup circuit operating current	BUP ^{Note 1}				0.05		μA
A/D converter	IADC ^{Notes 1, 8}	When	Normal mode, AV _{REFP} = V _{DD} = 5.0 V		1.3	2.4	mA
operating current		conversion at maximum speed	Low voltage mode, AV _{REFP} = V_{DD} = 3.0 V		0.5	1.0	mA
A/D converter reference voltage current	Adref ^{Note 1}				75.0		μA
Temperature sensor operating current	I _{TMPS} Note 1				105		μA
BGO operating current	BGO ^{Notes 1, 9}				2.00	12.20	mA
Self- programming operating current	_{FSP} Notes 1, 10				2.00	12.20	mA

(Notes and Remarks are listed on the next page.)

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Parameter	Symbol		Conditions		MIN.	TYP.	MAX.	Unit
24-Bit ΔΣ A/D	IDSAD ^{Notes 1, 11}	In 4 ch ΔΣ A/D cor	overter operation			1.45	2.30	mA
Converter operating		In 3 ch ΔΣ A/D cor	overter operation			1.14	1.85	mA
current		In 1 ch ΔΣΑ/D con	verter operation			0.52	0.94	mA
SNOOZE	ISNOZ ^{Notes 1, 12}	ADC operation	The mode is performed			0.50	0.80	mA
operating current			The A/D conversion opera performed, low voltage mo $V_{DD} = 3.0 V$			1.20	1.80	mA
		Simplified SPI (CS	I)/UART operation			0.70	1.05	mA
		DTC operation				2.20		mA
LCD operating current	_{LCD1} Notes 1, 13, 14	External resistance division method	f _{LCD} = f _{SUB} LCD clock = 128 Hz 1/3 bias, four-time-slices	V _{DD} = 5.0 V, V _{L4} = 5.0 V		0.06		μA
	I _{LCD2} Notes 1, 13	Internal voltage boosting method	f _{LCD} = fsuв LCD clock = 128 Hz 1/3 bias, four-time-slices	V _{DD} = 3.0 V, V _{L4} = 3.0 V (VLCD = 04H)		0.85		μA
				V _{DD} = 5.0 V, V _{L4} = 5.1 V (VLCD = 12H)		1.55		μA
	I _{LCD3} Notes 1, 13	Capacitor split method	f _{LCD} = f _{SUB} LCD clock = 128 Hz 1/3 bias, four-time-slices	V _{DD} = 3.0 V, V _{L4} = 3.0 V		0.20		μA

$(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{\text{Note } 15} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$
--

Notes 1. Current flowing to VDD. When the VBAT pin (battery backup power supply pin) is selected, current flowing to the VBAT.

- 2. When high speed on-chip oscillator and high-speed system clock are stopped.
- **3.** Current flowing to VRTC pin, including RTC power supply, subsystem clock oscillator circuit, and RTC.
- 4. Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and XT1 oscillator). The value of the current value of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and ITMKA, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 5. Current flowing only to the 8-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and XT1 oscillator). The value of the current value of the RL78 microcontrollers is the sum of the values of either IDD1 or IDD2, and ITMT, when the 8-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, IFIL should be added.
- 6. Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and IWDT when the watchdog timer operates.
- 7 Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of IDD1, IDD2 or IDD3 and ILVD when the LVD circuit operates.
- **8.** Current flowing only to the A/D converter. The current value of the RL78 microcontrollers is the sum of IDD1 or IDD2 and IADC when the A/D converter operates in an operation mode or the HALT mode.
- 9. Current flowing only during rewrite of 1 KB data flash memory.
- 10.Current flowing only during self programming.
- **11.**Current flowing only to the 24-bit $\Delta\Sigma$ A/D converter. The current value of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2}, and I_{DSAD} when the 24-bit $\Delta\Sigma$ A/D converter operates.
- 12. For shift time to the SNOOZE mode, see 26.3.3 SNOOZE mode in the RL78/I1C User's Manual.

- Notes 13. Current flowing only to the LCD controller/driver. The current value of the RL78 microcontrollers is the sum of the LCD operating current (ILCD1, ILCD2 or ILCD3) to the supply current (IDD1, or IDD2) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel. Conditions of the TYP. value and MAX. value are as follows.
 - Setting 20 pins as the segment function and blinking all
 - Selecting fsub for system clock when LCD clock = 128 Hz (LCDC0 = 07H)
 - Setting four time slices and 1/3 bias
 - **14.** Not including the current flowing into the external division resistor when using the external resistance division method.
 - **15.** Either VDD or VBAT is selected by the battery backup function.
- Remarks 1. fill: Low-speed on-chip oscillator clock frequency
 - **2.** fsub: Subsystem clock frequency (XT1 clock oscillation frequency)
 - **3.** fclk: CPU/peripheral hardware clock frequency
 - 4. Temperature condition of the TYP. value is $T_A = 25^{\circ}C$



2.4 AC Characteristics

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD}0} = \text{EV}_{\text{DD}1} \le \text{V}_{\text{DD}}^{\text{Note } 1} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS0}}$	ss1 = 0 V)
--	------------

(1/2)

$(1A = -40 \ 10 + 85 \ C, 1.7)$				25.5 V, VSS - LVSS0 - LVSS1 - UV)						
Items	Symbol		Conditic	ins	MIN.	TYP.	MAX.	Unit		
Instruction cycle (minimum	Тсү	Main system	HS (high-speed	$2.8 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.03125		1	μs		
instruction execution time)		clock (fmain)	main) mode	$2.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} < 2.8 \text{ V}$	0.04167		1	μs		
		operation		$2.5 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} < 2.7 \text{ V}$	0.0625		1	μs		
				$2.4 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} < 2.5 \text{ V}$	0.08333		1	μs		
				$2.1 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note 1}} < 2.4 \text{ V}$	0.16667		1	μs		
			LS (low-speed main) mode	$1.9 \text{ V} \le \text{V}_{\text{DD}}^{\text{Note 1}} \le 5.5 \text{ V}$	0.125		1	μs		
			LS (low-speed main) mode @4 MHz	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.25		1	μs		
			LP (low-power main) mode	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	1		2	μs		
			LV (low-voltage main) mode	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.25		1	μs		
		Subsystem cl operation	ock (fsuв)	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	28.5	30.5	31.3	μs		
		In the self programming mode	main) mode	$2.8 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.03125		1	μs		
				$2.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 2.8 \text{ V}$	0.04167		1	μs		
				$2.5 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 2.7 \text{ V}$	0.0625		1	μs		
			$2.4 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 2.5 \text{ V}$	0.08333		1	μs			
				$2.1 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 2.4 \text{ V}$	0.16667		1	μs		
			LS (low-speed main) mode	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.125		1	μs		
			LV (low-voltage main) mode	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	0.25		1	μs		
External system clock	fex	2.7 V ≤ V _{DD} ^{Not}	^{e 1} ≤ 5.5 V		1		20	MHz		
frequency		2.5 V ≤ V _{DD} ^{Not}	^{e 1} < 2.7 V		1		16	MHz		
		$2.4 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Not}}$	^{e 1} < 2.5 V		1		12	MHz		
		1.9 V ≤ V _{DD} ^{Not}	^{e 1} < 2.4 V		1		8	MHz		
		1.7 V ≤ V _{DD} ^{Not}	^{e 1} < 1.9 V		1		4	MHz		
	fexs				32		35	kHz		
External system clock input	t _{EXH} ,	2.7 V ≤ V _{DD} ^{Not}	^{æ 1} ≤ 5.5 V		24			ns		
high-level width, low-level	texL	2.5 V ≤ V _{DD} ^{Not}	^{e 1} < 2.7 V		30			ns		
width		$2.4 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Not}}$	^{e 1} < 2.5 V		40			ns		
		1.9 V ≤ V _{DD} ^{Not}	^{e 1} < 2.4 V		60			ns		
		1.7 V ≤ V _{DD} ^{Not}	^{e 1} < 1.9 V	120			ns			
	texнs, texls				13.7			μs		
TI00 to TI07 input high-level width, low-level width	tтıн, tтı∟				1/fмск+10			ns ^{Note 2}		

(Notes and Remark are listed on the next page.)



(2/2)

Items	Symbol	Con	ditions	MIN.	TYP.	MAX.	Unit
TO00 to TO07 output	fто	HS (high-speed main)	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			16	MHz
frequency		mode	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} < 4.0 \text{ V}$			8	MHz
			$2.4 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$			4	MHz
			2.1 V ≤ EV _{DD} < 2.4 V			4	MHz
		LS (low-speed main) mode	$1.9 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			4	MHz
		LP (low-power main) mode	$1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			0.5	MHz
		LV (low-voltage main) mode	1.7 V ≤ EV _{DD} ≤ 5.5 V			2	MHz
PCLBUZ0, PCLBUZ1 output	f PCL	HS (high-speed main)	$4.0 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			16	MHz
frequency		mode	2.7 V ≤ EV _{DD} < 4.0 V			8	MHz
			$2.4 \text{ V} \le \text{EV}_{\text{DD}} < 2.7 \text{ V}$			4	MHz
			$2.1 \text{ V} \leq \text{EV}_{\text{DD}} < 2.4 \text{ V}$			4	MHz
		LS (low-speed main) mode	$1.9 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			4	MHz
		LP (low-power main) mode	1.9 V ≤ EV _{DD} ≤ 5.5 V			1	MHz
		LV (low-voltage main)	1.9 V ≤ EV _{DD} ≤ 5.5 V			4	MHz
		mode	1.7 V ≤ EV _{DD} < 1.9 V			2	MHz
Interrupt input high-level	tinth,	INTP0	$1.7 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 1}} \leq 5.5 \text{ V}$	1			μs
width, low-level width	t intl	INTP1 to INTP7	$1.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	1			μs
Key interrupt input low-level	t kr	KR0 to KR7	$1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$	250			ns
width			1.7 V ≤ EV _{DD} < 1.9 V	1			μs
RESET low-level width	trsl			10			μs

(T_A = -40 to +85°C, 1.7 V ≤ EV_{DD0} = EV_{DD1} ≤ V_{DD^{Note 1} ≤ 5.5 V, Vss = EV_{SS0} = EV_{SS1} = 0 V)}

Notes 1. Either V_{DD} or VBAT is selected by the battery backup function.

2. The following conditions are required for low voltage interface: $1.9 \text{ V} \le \text{V}_{\text{DD}} < 2.7 \text{ V}$: MIN. 125 ns

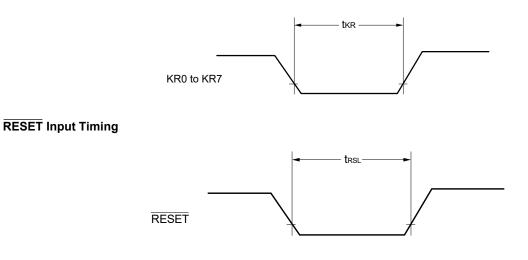
 $\label{eq:result} \textbf{Remark} \hspace{0.2cm} \textit{f}_{\text{MCK}} \text{: Timer array unit operation clock frequency}$

(Operation clock to be set by the CKSmn0, CKSmn1 bits of timer mode register mn (TMRmn) m: Unit number (m = 0), n: Channel number (n = 0 to 7))

AC Timing Test Points Vін/Vон Viн/Voн Test points Vil/Vol VIL/VOL **External System Clock Timing** – 1/f_{EX} – texl -– tехн – 0.7VDD (MIN.) EXCLK 0.3VDD (MAX.) – 1/f_{EXS} – texus -– texns – 0.7VRTC (MIN.) EXCLKS 0.3VRTC (MAX.) **TI/TO Timing** · tтін t⊤i∟ TI00 to TI07 **1/f**то TO00 to TO07 Interrupt Request Input Timing tintl · tinth -INTP0 to INTP7



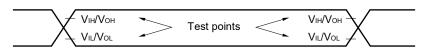
Key interrupt Input Timing





2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

(1) During communication at same potential (UART mode) (dedicated baud rate generator output) (T_A = -40 to +85°C, 1.7 V ≤ EVDD0 = EVDD1 ≤ VDD^{Note 4} ≤ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

	.	0		HS (high-speed			"				
Parameter	Symbol	Conditions		gh-speed ı) Mode	•	v-speed Mode		w-power ı) Mode	``	w-voltage ı) Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate ^{Note 1}		$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		fмск/6 ^{№оte 2}		fмск/6 ^{Note} 2		fмск/6 ^{№te 2}		fмск/6 ^{№оte 2}	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$		4.0		1.3		0.1		0.6	Mbps
		$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		ƒмск/6 ^{№оte 2}		fмск/6 ^{Note} 2		fмск/6 ^{№te 2}		fмск/6 ^{№оte 2}	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$		1.0		1.3		0.1		0.6	Mbps
		$1.8 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		fмск/6 ^{Note 2}		fмск/6 ^{Note} 2		fмск/6 ^{Note 2}		fмск/6 ^{Note 2}	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$		1.0		1.3		0.1		0.6	Mbps
		1.7 V ≤ V _{DD} ≤ 5.5 V								fмск/6 ^{Note 2}	bps
		Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 3}$								0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. The following conditions are required for low voltage interface.

 $2.4 \text{ V} \leq \text{EV}_{\text{DD}} < 2.7 \text{ V}$: MAX. 2.6 Mbps

 $1.9 \text{ V} \leq \text{EV}_{\text{DD}} < 2.4 \text{ V}$: MAX. 1.3 Mbps

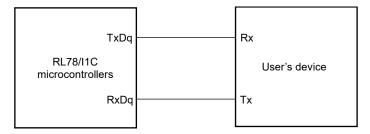
3. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

HS (high-speed main) mode: 32 MHz (2.8 V ≤ EV_{DD} ≤ 5.5 V), 24 MHz (2.7 V ≤ EV_{DD} ≤ 5.5 V),

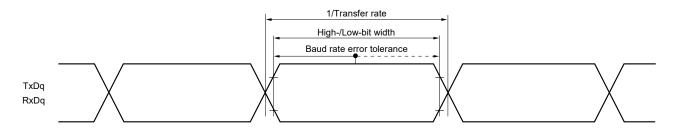
- 16 MHz (2.5 V \leq EV_{DD} \leq 5.5 V), 12 MHz (2.4 V \leq EV_{DD} \leq 5.5 V),
- 6 MHz (2.1 V \leq EV_{DD} \leq 5.5 V),
- LS (low-speed main) mode: 8 MHz (1.9 V \leq EV_{DD} \leq 5.5 V), 4 MHz (1.9 V \leq EV_{DD} \leq 5.5 V)
- LP (low-power main) mode: 1 MHz (1.9 V \leq EV_{DD} \leq 5.5 V)
- LV (low-voltage main) mode: $4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$
- 4. Either V_{DD} or VBAT is selected by the battery backup function.

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)



UART mode bit width (during communication at same potential) (reference)



- **Remarks 1.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)
 - fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 - m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))



(2) During communication at same potential (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output)

Parameter	Symbol	Co	onditions	HS (higl main)	h-speed Mode	LS (low main)	•	LP (low main)	•	LV (low- main)	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkCY1	2.7 V ≤	EV _{DD} ≤ 5.5 V	125		500		4000		1000		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	250		500		4000		1000		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	500		500		4000		1000		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V	1000		1000		4000		1000		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			1000		4000		1000		ns
SCKp high-/low-level	tкнı, tĸ∟ı	4.0 V ≤	EV _{DD} ≤ 5.5 V	tксү1/ 2 – 12		tксү1/ 2 – 50		tксү1/ 2 — 50		tксү1/ 2 – 50		ns
width		2.7 V ≤	EV _{DD} ≤ 5.5 V	tксү1/ 2 – 18		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 — 50		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	tксү1/ 2 – 38		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 — 50		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 — 50		tксү1/ 2 – 50		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V			tксү1/ 2 – 100		tксү1/ 2 – 100		tксү1/ 2 – 100		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			tксү1/ 2 – 100		tксү1/ 2 – 100		tксү1/ 2 – 100		ns
SIp setup time (to	tsik1	4.0 V ≤	EV _{DD} ≤ 5.5 V	44		110		110		110		ns
SCKp↑) ^{Note 1}		2.7 V ≤	EV _{DD} ≤ 5.5 V	44		110		110		110		ns
		2.4 V ≤	EV _{DD} ≤ 5.5 V	75		110		110		110		ns
		1.9 V ≤	EV _{DD} ≤ 5.5 V	110		110		110		110		ns
		1.8 V ≤	EV _{DD} ≤ 5.5 V	220		220		220		220		ns
		1.7 V ≤	EV _{DD} ≤ 5.5 V			220		220		220		ns
Slp hold time	tksi1	1.8 V ≤	EV _{DD} ≤ 5.5 V	19		19		19		19		ns
(from SCKp↑) ^{Note 2}		1.7 V ≤	EV _{DD} ≤ 5.5 V			19		19		19		ns
Delay time from SCKp↓ to SOp	tkso1	C = 30 pF ^{Note 3}	1.8 V ≤ EV _{DD} ≤ 5.5 V		25		25		25		25	ns
output ^{Note 3}			1.7 V ≤ EV _{DD} ≤ 5.5 V				25		25		25	ns

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}\text{DD} = \text{EV}\text{DD} 1 \le \text{V}\text{DD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{sso} = \text{EV}\text{sso} = 0 \text{ V})$

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. C is the load capacitance of the SCKp and SOp output lines.

4. Either V_{DD} or VBAT is selected by the battery backup function.

Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

- **Remarks 1.** p: CSI number (p = 00, 10, 30), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM numbers (g = 0, 1, 8)
 - fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00, 10, 30))

(3) During communication at same potential (Simplified SPI (CSI) mode) (slave mode, SCKp... external clock input)

Parameter	Symb ol	C	Conditions	HS (high- main) N	•	LS (low- main) N	•	LP (low- main) N		LV (low-v main) N	-	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle	tkCY2	4.0 V ≤	20 MHz < fмск	8/fмск		_		_		_		ns
time ^{Note 4}		EV _{DD} ≤ 5.5 V	fмск ≤ 20 MHz	6/fмск		6/fмск		6/fмск		6/fмск		ns
		2.7 V ≤	16 MHz < fмск	8/fмск		-		-		_		ns
		EV _{DD} ≤ 5.5 V	fмск ≤ 16 MHz	6/fмск		6/fмск		6/fмск		6/fмск		ns
		2.4 V ≤ E	$2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			6/fмск and 500		6/fмск and 500		6/fмск and 500		ns
		1.9 V ≤ E	EV _{DD} ≤ 5.5 V	6/fмск and 750		6/fмск and 750		6/fмск and 750		6/fмск and 750		ns
		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			6/fмск and 1500		6/fмск and 1500		6/fмск and 1500		ns
SCKp high-/low-	tкн2, tкL2	4.0 V ≤ E	EVdd ≤ 5.5 V	tксү2/ 2 – 7		tксү2/ 2 – 7		tксү2/ 2 – 7		tксү2/ 2 – 7		ns
level width		2.7 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 8		tксү2/ 2 – 8		tксү2/ 2 – 8		tксү2/ 2 – 8		ns
	1.9 V	1.9 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 18		tксү2/ 2 – 18		tксү2/ 2 – 18		tксү2/ 2 – 18		ns
		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			tксү2/ 2 – 66		tксү2/ 2 – 66		tксү2/ 2 – 66		ns
SIp setup	tsik2	2.7 V ≤ E	EVdd ≤ 5.5 V	1/fмск+20		1/fмск+30		1/fмск+30		1/fмск+30		ns
time (to SCKp↑) ^{Note 1}		1.9 V ≤ E	EVdd ≤ 5.5 V	1/fмск+30		1/fмск+30		1/fмск+30		1/fмск+30		ns
SCKp ⁺)		1.8 V ≤ E	EV _{DD} ≤ 5.5 V	1/fмск+40		1/fмск+40		1/fмск+40		1/fмск+40		ns
		1.7 V ≤ E	EV _{DD} ≤ 5.5 V			1/fмск+40		1/fмск+40		1/fмск+40		ns
SIp hold	tksi2	2.1 V ≤ E	EVDD ≤ 5.5 V	1/fмск+31		1/fмск+31		1/fмск+31		1/fмск+31		ns
time (from SCKp↑) ^{Note 1}		1.9 V ≤ E	EVdd ≤ 5.5 V			1/fмск+31		1/fмск+31		1/fмск+31		ns
		1.7 V ≤ E	Vdd ≤ 5.5 V							1/fмск+250		ns
Delay time from SCKp↓	tĸso2	C = 30 pF ^{Note 3}	2.7 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 44		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
to SOp output ^{Note 2}			2.4 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 75		2/fмск+ 110		2/fмск+ 110		2/fмск+ 110	ns
			1.9 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 100		2/fмск+ 110		2/fмск+ 110		2/f _{мск} + 110	ns
			1.8 V ≤ EV _{DD} ≤ 5.5 V		2/fмск+ 220		2/fмск+ 220		2/f _{мск} + 220		2/f _{мск} + 220	ns
			1.7 V ≤ EV _{DD} ≤ 5.5 V				2/fмск+ 220		2/f _{мск} + 220		2/f _{мск} + 220	ns

(Notes, Caution, and Remarks are listed on the next page.)

- Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - 3. C is the load capacitance of the SOp output lines.
 - 4. Transfer rate in the SNOOZE mode: MAX. 1 Mbps
 - 5. Either V_{DD} or VBAT is selected by the battery backup function.

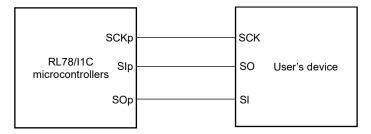
Caution Select the normal input buffer for the SIp pin and SCKp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

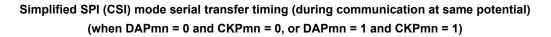
- **Remarks 1.** p: CSI number (p = 00, 10, 30), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM number (g = 0, 1, 8)
 - fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

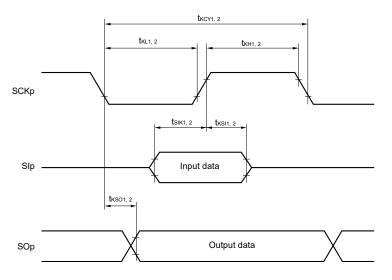
m: Unit number, n: Channel number (mn = 00, 10, 30))



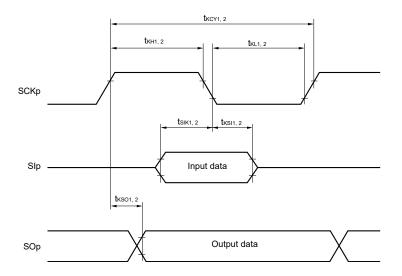
Simplified SPI (CSI) mode connection diagram (during communication at same potential)

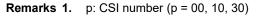






Simplified SPI (CSI) mode serial transfer timing (during communication at same potential) (when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0)





2. m: Unit number, n: Channel number (mn = 00, 10, 30)

(4) During communication at same potential (simplified I²C mode)

(T_A = -40 to +85°C, 1.7 V ≤ EVDD0 = EVDD1 ≤ VDD^{Note 3} ≤ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

(1/2)

Parameter	Symbol	Conditions	HS (high-s		•	/-speed	LP (low	•		-voltage	Unit
			MIN.	MAX.	main) MIN.	MAX.	MIN.	Mode MAX.	MIN.	Mode MAX.	-
SCLr clock frequency	fsc∟	2.7 V ≤ EV _{DD} ≤ 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ		1000 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}	kHz
		1.9 V ≤ EV _{DD} ≤ 5.5 V, C _b = 100 pF, R _b = 3 kΩ		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}		400 ^{Note 1}	kHz
		$1.9 V \le EV_{DD} < 2.7 V,$ $C_b = 100 \text{ pF}, R_b = 5 \text{ k}\Omega$		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$1.8 V \le EV_{DD} < 1.9 V,$ C _b = 100 pF, R _b = 5 kΩ		250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}	kHz
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ				250 ^{Note 1}		250 ^{Note 1}		250 ^{Note 1}	kHz
Hold time when SCLr =	t∟ow	2.7 V ≤ EV _{DD} ≤ 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1150		1150		1150		ns
"L"		1.9 V ≤ EV _{DD} ≤ 5.5 V, C₅ = 100 pF, R₅ = 3 kΩ	1150		1150		1150		1150		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C₅ = 100 pF, R₅ = 5 kΩ	1550		1550		1550		1550		ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1850		1850		1850		1850		ns
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ			1850		1850		1850		ns
Hold time when SCLr =	tніgн	2.7 V ≤ EV _{DD} ≤ 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1150		1150		1150		ns
"H"		1.9 V ≤ EV _{DD} ≤ 5.5 V, C _b = 100 pF, R _b = 3 kΩ	1150		1150		1150		1150		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1550		1550		1550		1550		ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1850		1850		1850		1850		ns
		1.7 V ≤ EV _{DD} < 1.9 V, C₀ = 100 pF, R₀ = 5 kΩ			1850		1850		1850		ns
Data setup time	tsu:dat	2.7 V ≤ EV _{DD} ≤ 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	1/f _{MCK} + 85 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		ns
(reception)		1.9 V ≤ EV _{DD} ≤ 5.5 V, C _b = 100 pF, R _b = 3 kΩ	1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1, 2}		1/f _{MCK} + 145 ^{Notes 1,2}		1/f _{MCK} + 145 ^{Notes 1, 2}		ns
		1.9 V ≤ EV _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1/f _{MCK} + 230 ^{Notes 1, 2}		1/f _{MCK} + 230 ^{Notes 1, 2}		1/f _{MCK} + 230 ^{Notes 1,2}		1/f _{MCK} + 230 ^{Notes 1, 2}		ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	1/fмск + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1,2}		1/f _{MCK} + 290 ^{Notes 1,2}		ns
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ			1/f _{MCK} + 290 ^{Notes 1, 2}		1/f _{MCK} + 290 ^{Notes 1,2}		1/f _{MCK} + 290 ^{Notes 1, 2}		ns

(Notes, Caution, and Remarks are listed on the next page.)



(2/2)

Parameter	Symbol	Conditions	、 U	HS (high-speed main) Mode		LS (low-speed main) Mode		LP (low-power main) Mode		LV (low-voltage main) Mode	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data hold time	thd:dat	2.7 V ≤ EV _{DD} ≤ 5.5 V, C _b = 50 pF, R _b = 2.7 kΩ	0	305	0	305	0	305	0	305	ns
(transmission)	1.9 V ≤ EV _{DD} ≤ 5.5 V, C₀ = 100 pF, R₀ = 3 kΩ	0	355	0	355	0	355	0	355	ns	
		1.9 V ≤ EV _{DD} < 2.7 V, C₀ = 100 pF, R₀ = 5 kΩ	0	405	0	405	0	405	0	405	ns
		1.8 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	0	405	0	405	ns
		1.7 V ≤ EV _{DD} < 1.9 V, C _b = 100 pF, R _b = 5 kΩ			0	405	0	405	0	405	ns

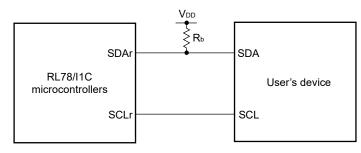
 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}\text{DD} = \text{EV}\text{DD} 1 \le \text{V}\text{DD}^{\text{Note } 3} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{sso} = \text{EV}\text{sso} = 0 \text{ V})$

Notes 1. The value must also be equal to or less than fmck/4.

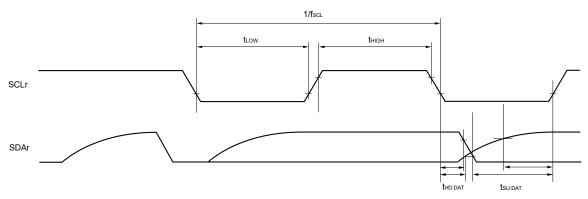
Set the fMCK value to keep the hold time of SCLr = "L" and SCLr = "H". 2

3. Either VDD or VBAT is selected by the battery backup function.

Simplified I²C mode connection diagram (during communication at same potential)



Simplified I²C mode serial transfer timing (during communication at same potential)



- Caution Select the normal input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the normal output mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg).
- Remarks 1. Rb[Ω]:Communication line (SDAr) pull-up resistance, Cb[F]: Communication line (SDAr, SCLr) load capacitance
 - 2. r: IIC number (r = 00, 10, 30), g: PIM and POM number (g = 0, 1, 8)
 - 3. fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00, 02, 12))

(5) Communication at different potential (1.9 V, 2.5 V, 3 V) (UART mode) (1/2)

Parameter	Symbol		Conditions		gh-speed 1) Mode		ow-speed n) Mode			LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		Reception	$4.0 V \le EV_{DD} \le 5.5 V$, $2.7 V \le V_b \le 4.0 V$		fмск/6 ^{Note 1}		fмск/6 ^{Note 1}		fмск/6 ^{Note 1}		fмск/6 ^{Note 1}	bps
		Rec	Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 4}$		5.3		1.3		0.1		0.6	Mbps
			$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V$		fмск/6 ^{Note 1}		f _{мск} /6 ^{Note 1}		ƒмск/6 ^{№оtе 1}		fмск/6 ^{Note 1}	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 4}$		5.3		1.3		0.1		0.6	Mbps
			$1.9 V \le EV_{DD} < 3.3 V,$ $1.8 V \le V_b \le 2.0 V$		fмск/6 Notes 1 to 3		fмск/6 Notes 1, 2		fмск/6 Notes 1, 2		fмск/6 Notes 1, 2	bps
			Theoretical value of the maximum transfer rate $f_{MCK} = f_{CLK}^{Note 4}$		5.3		1.3		0.1		0.6	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps only.

2. Use it with $EV_{DD} \ge V_b$.

The following conditions are required for low voltage interface.
 2.4 V ≤ EV_{DD} < 2.7 V: MAX. 2.6 Mbps
 1.9 V ≤ EV_{DD} < 2.4 V: MAX. 1.3 Mbps

4. The maximum operating frequencies of the CPU/peripheral hardware clock (fcLK) are:

HS (high-speed main) mode: $32 \text{ MHz} (2.8 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 24 \text{ MHz} (2.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 16 \text{ MHz} (2.5 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 12 \text{ MHz} (2.4 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 6 \text{ MHz} (2.1 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 12 \text{ MHz} (2.4 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 6 \text{ MHz} (2.1 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 8 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}), 4 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}) 1 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}) 1 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V})$ LP (low-power main) mode:1 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V}) 4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V})LV (low-voltage main) mode:4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{DD} \le 5.5 \text{ V})

- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** V_b[V]: Communication line voltage
 - **2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)
 - fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(5) Communication at different potential (1.8 V, 2.5 V, 3 V) (UART mode) (2/2)

Parameter	Symbol		Conditions		HS (high-speed main) Mode		v-speed Mode	LP (low-power main) Mode		LV (low-voltage main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Transfer rate		ission	$4.0 V \le EV_{DD} \le 5.5 V$, $2.7 V \le V_b \le 4.0 V$		Notes 1, 2		Notes 1, 2		Notes 1, 2		Notes 1, 2	bps
		Transmission	Theoretical value of the maximum transfer rate ^{Note 9} $C_b = 50 \text{ pF}, R_b = 1.4 \text{ k}\Omega,$ $V_b = 2.7 \text{ V}$		2.8 ^{Note 3}		2.8 ^{Note 3}		2.8 ^{Note 3}		2.8 ^{Note 3}	Mbps
			$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V$		Notes 2, 4		Notes 2, 4		Notes 2, 4		Notes 2, 4	bps
			Theoretical value of the maximum transfer rate ^{Note 9} $C_b = 50 \text{ pF}, R_b = 2.7 \text{ k}\Omega,$ $V_b = 2.3 \text{ V}$		1.2 ^{Note 5}		1.2 ^{Note 5}		1.2 ^{Note 5}		1.2 ^{Note 5}	Mbps
			$1.9 V \le EV_{DD} < 3.3 V,$ $1.6 V \le V_b \le 2.0 V$		Notes 2, 6, 7		Notes 2, 6, 7		Notes 2, 6, 7		Notes 2, 6, 7	bps
			Theoretical value of the maximum transfer rate ^{Note 9} $C_b = 50 \text{ pF}, R_b = 5.5 \text{ k}\Omega,$ $V_b = 1.6 \text{ V}$		0.43 ^{Note 8}		0.43 ^{Note 8}		0.43 ^{Note 8}		0.43 ^{Note 8}	Mbps

(T_A = -40 to +85°C, 1.9 V ≤ EVDD0 = EVDD1 ≤ VDD^{Note 10} ≤ 5.5 V, Vss = EVss0 = EVss1 = 0 V)

Notes 1. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 4.0 V \leq EV_{DD} \leq 5.5 V and 2.7 V \leq V_b \leq 4.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate } \times 2} - \{-C_b \times R_b \times \ln (1 - \frac{2.2}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$$

- * This value is the theoretical value of the relative difference between the transmission and reception sides.
- 2. Transfer rate in the SNOOZE mode is 4800 bps only.
- This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.
- 4. The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 2.7 V \leq EV_{DD} < 4.0 V and 2.3 V \leq V_b \leq 2.7 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{2.0}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) =
$$\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{(\frac{1}{(\text{Transfer rate})} \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

- **Notes 5.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 4** above to calculate the maximum transfer rate under conditions of the customer.
 - 6. Use it with $EV_{DD} \ge V_b$.
 - **7.** The smaller maximum transfer rate derived by using fMCK/6 or the following expression is the valid maximum transfer rate.

Expression for calculating the transfer rate when 1.9 V \leq EV_{DD} < 2.7 V and 1.6 V \leq V_b \leq 2.0 V

Maximum transfer rate =
$$\frac{1}{\{-C_b \times R_b \times \ln (1 - \frac{1.5}{V_b})\} \times 3}$$
 [bps]

Baud rate error (theoretical value) = $\frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{(\frac{1}{\text{Transfer rate}}) \times \text{Number of transferred bits}} \times 100 [\%]$

* This value is the theoretical value of the relative difference between the transmission and reception sides.

- **8.** This value as an example is calculated when the conditions described in the "Conditions" column are met. Refer to **Note 7** above to calculate the maximum transfer rate under conditions of the customer.
- **9.** The maximum operating frequencies of the CPU/peripheral hardware clock (fCLK) are:
 - HS (high-speed main) mode:
 $32 \text{ MHz} (2.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 24 \text{ MHz} (2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 16 \text{ MHz} (2.5 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 12 \text{ MHz} (2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 6 \text{ MHz} (2.1 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 12 \text{ MHz} (2.4 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 6 \text{ MHz} (2.1 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 8 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 4 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}) 12 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 14 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 14 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 14 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}) 12 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 14 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}), 14 \text{ MHz} (1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$

 LV (low-voltage main) mode:
 $4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$ $4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$ $4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$ $4 \text{ MHz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$ $4 \text{ Mz} (1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V})$ $4 \text{ Mz} (1.7 \text{ V} \le 1.0 \text{ V} \le 1.0 \text{ V} \le 1.0 \text{ V} \le 1.0 \text{ V} = 1.0 \text{ Mz}$ $4 \text{ Mz} (1.0 \text{ V} \le 1.0 \text{ W} = 1$
- **10.** Either VDD or VBAT is selected by the battery backup function.
- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** $R_b[\Omega]$:Communication line (TxDq) pull-up resistance,

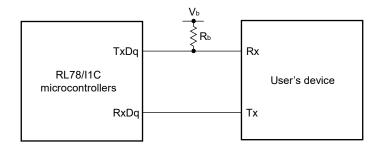
Cb[F]: Communication line (TxDq) load capacitance, Vb[V]: Communication line voltage

2. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)

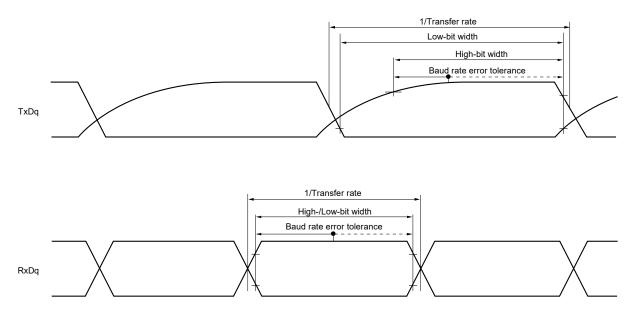
 fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

UART mode connection diagram (during communication at different potential)







UART mode bit width (during communication at different potential) (reference)

- Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_H and V_{IL}, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** $R_b[\Omega]$: Communication line (TxDq) pull-up resistance, $V_b[V]$: Communication line voltage
 - **2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 5, 8)



(6) Communication at different potential (2.5 V, 3 V) (fmck/2) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only) (1/2)

Parameter	Symbol		Conditions	HS (high- main) N	•	LS (low- main) l	•	LP (low- _l main) N		LV (low-v main) N	-	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tксүı	tксү1 ≥ 2/fс∟к	$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 20 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$	200		1150		1150		1150		ns
			$\begin{array}{l} 2.7 \; V \leq E V_{DD} < 4.0 \; V, \\ 2.3 \; V \leq V_b \leq 2.7 \; V, \\ C_b = 20 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	300		1150		1150		1150		ns
SCKp high- level width	tкнı	2.7 V ≤	≤ EV _{DD} ≤ 5.5 V, ≤ V _b ≤ 4.0 V,) pF, R _b = 1.4 kΩ	tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
		2.3 V ≤	$S = V_{DD} < 4.0 V,$ $S V_b \le 2.7 V,$ $O pF, R_b = 2.7 kΩ$	tксү1/ 2 – 120		tксү1/ 2 – 120		tксү1/ 2 – 120		tксү1/ 2 – 120		ns
SCKp low- level width	tĸ∟ı	2.7 V ≤	$S = V_{DD} \le 5.5 V,$ $S V_b \le 4.0 V,$ $O pF, R_b = 1.4 kΩ$	tксү1/ 2 – 7		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
		2.3 V ≤	$S = V_{DD} < 4.0 V,$ $S V_b \le 2.7 V,$ $O pF, R_b = 2.7 kΩ$	tксү1/ 2 – 10		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsik1	2.7 V ≤	≤ EV _{DD} ≤ 5.5 V, ≤ V _b ≤ 4.0 V,) pF, R _b = 1.4 kΩ	58		479		479		479		ns
		2.3 V ≤	≦ EV _{DD} < 4.0 V, 5 V _b ≤ 2.7 V, 0 pF, R _b = 2.7 kΩ	121		479		479		479		ns
SIp hold time (from SCKp↑) ^{Note 1}	tksi1	2.7 V ≤	5 EV₀₀ ≤ 5.5 V, 5 V₀ ≤ 4.0 V, 0 pF, R₀ = 1.4 kΩ	10		10		10		10		ns
		2.3 V ≤	5 EV _{DD} < 4.0 V, 5 V _b ≤ 2.7 V, 0 pF, R _b = 2.7 kΩ	10		10		10		10		ns
Delay time from SCKp↓ to SOp	tĸso1	2.7 V ≤	$S = V_{DD} \le 5.5 V,$ $S V_b \le 4.0 V,$ $O pF, R_b = 1.4 kΩ$		60		60		60		60	ns
output ^{Note 1}		2.3 V ≤	5 EV _{DD} < 4.0 V, 5 V _b ≤ 2.7 V, 0 pF, R _b = 2.7 kΩ		130		130		130		130	ns
SIp setup time (to SCKp↓) ^{Note 2}	tsıĸı	2.7 V ≤	5 EV _{DD} ≤ 5.5 V, 5 V _b ≤ 4.0 V, 0 pF, R _b = 1.4 kΩ	23		110		110		110		ns
		2.3 V ≤	Ξ EV _{DD} < 4.0 V, Ξ V _b ≤ 2.7 V, Ο pF, R _b = 2.7 kΩ	33		110		110		110		ns

1	$(T_{A} = -40 \text{ to } +85^{\circ}\text{C})$	$2.7 V \leq EV_{DD0} = EV_{DD1}$	< VppNote 3 < 5 5 V	, Vss = EVss0 = EVss1 = 0 V)
	(IA40 10 +05 C	$, \mathbf{Z} \cdot \mathbf{I} = \mathbf{V} \mathbf{D} \mathbf{U} \mathbf{U} - \mathbf{C} \mathbf{V} \mathbf{D} \mathbf{U}^{T}$	\geq VDD \geq 5.5 V,	, vss - cvssu - cvssu - u vj

(Notes, Caution, and Remarks are listed on the next page.)



(6) Communication at different potential (2.5 V, 3 V) (fMck/2) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output, corresponding CSI00 only) (2/2)

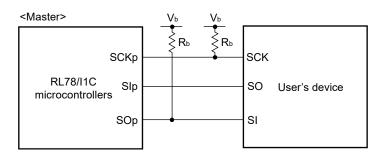
Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		LP (low-power main) Mode		LV (low-voltage main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp hold time (from SCKp↓) ^{Note 2}	tksi1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 20 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	10		10		10		10		ns
		$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V,$ $C_b = 20 pF, R_b = 2.7 k\Omega$	10		10		10		10		ns
Delay time from SCKp↑ to SOp	tkso1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 20 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$		10		10		10		10	ns
output ^{Note 2}		$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V,$ $C_b = 20 pF, R_b = 2.7 k\Omega$		10		10		10		10	ns

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.7 \text{ V} \le \text{EV}\text{DD0} = \text{EV}\text{DD1} \le \text{V}\text{DD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{ss0} = \text{EV}\text{ss1} = 0 \text{ V})$

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

- 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.
- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_H and V_L, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)



- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)

 fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).

m: Unit number, n: Channel number (mn = 00, 02, 12))

4. This specification is valid only when CSI00's peripheral I/O redirect function is not used.

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (fmck/4) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (1/2)

Parameter	Symbol		Conditions	HS (higl main)	•	LS (low- main) I	•	LP (low main)	•	LV (low-v main) I	-	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t ксү1	tксү1 ≥ 4/fс∟к	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	300		1150		1150		1150		ns
			$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	500		1150		1150		1150		ns
			$1.9 V \le EV_{DD} < 3.3 V,$ $1.6 V \le V_b \le 2.0 V,$ $C_b = 30 pF, R_b = 5.5 k\Omega$	1150		1150		1150		1150		ns
SCKp high- level width	tкнı	2.7 V ≤	$EV_{DD} \le 5.5 \text{ V},$ $V_b \le 4.0 \text{ V},$ p pF, $R_b = 1.4 \text{ k}\Omega$	tксү1/ 2 – 75		tксү1/ 2 – 75		tксү1/ 2 – 75		tксү1/ 2 – 75		ns
		2.3 V ≤	$EV_{DD} < 4.0 V,$ $V_b \le 2.7 V,$ p pF, $R_b = 2.7 k\Omega$	tксү1/ 2 – 170		tксү1/ 2 – 170		tксү1/ 2 – 170		tксү1/ 2 – 170		ns
		1.6 V ≤	$\label{eq:bound} \begin{split} ^{te4} &\leq EV_{DD} < 3.3 \ V, \\ V_b &\leq 2.0 \ V^{Note3}, \\ 0 \ pF, \ R_b &= 5.5 \ k\Omega \end{split}$	tксү1/ 2 – 458		tксү1/ 2 – 458		tксү1/ 2 – 458		tксү1/ 2 – 458		ns
SCKp low- level width	tĸ∟1	2.7 V ≤	$EV_{DD} \le 5.5 \text{ V},$ Vb $\le 4.0 \text{ V},$ 0 pF, Rb = 1.4 k Ω	tксү1/ 2 – 12		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
		2.3 V ≤	$EV_{DD} < 4.0 V,$ $V_b \le 2.7 V,$ p pF, $R_b = 2.7 k\Omega$	tксү1/ 2 – 18		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
		1.6 V ≤	$t^{te 4} \le EV_{DD} < 3.3 V,$ $V_{b} \le 2.0 V^{Note 3},$ $0 pF, R_{b} = 5.5 k\Omega$	tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		tксү1/ 2 – 50		ns
SIp setup time (to SCKp↑) ^{Note 1}	tsik1	2.7 V ≤	$\begin{split} & EV_{DD} \leq 5.5 \ V, \\ & V_{b} \leq 4.0 \ V, \\ & pF, \ R_{b} = 1.4 \ k\Omega \end{split}$	81		479		479		479		ns
		2.3 V ≤	$EV_{DD} < 4.0 V,$ $V_b \le 2.7 V,$ $pF, R_b = 2.7 k\Omega$	177		479		479		479		ns
		1.6 V ≤	$\begin{split} & EV_{DD} < 3.3 \ V, \\ & V_{b} \leq 2.0 \ V^{Note 3}, \\ & pF, \ R_{b} = 5.5 \ k\Omega \end{split}$	479		479		479		479		ns

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EV}\text{DD0} = \text{EV}\text{DD1} \le \text{V}\text{DD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{ss0} = \text{EV}\text{ss1} = 0 \text{ V})$

(Notes, Caution and Remarks are listed on the page after the next page.)

(7) Communication at different potential (1.8 V, 2.5 V, 3 V) (fmck/4) (Simplified SPI (CSI) mode) (master mode, SCKp... internal clock output) (2/2)

Parameter	Symbol	Conditions		h-speed Mode		/-speed Mode		/-power Mode		-voltage Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp hold time (from SCKp↑) ^{Note 1}	tksi1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	19		19		19		19		ns
		$2.7 V \le EV_{DD} < 4.0 V,$ $2.3 V \le V_b \le 2.7 V,$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$	19		19		19		19		ns
		1.9 V ≤ EV _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V ^{Note 3} , C _b = 30 pF, R _b = 5.5 kΩ	19		19		19		19		ns
Delay time from SCKp↓ to	tkso1	4.0 V ≤ EV _{DD} ≤ 5.5 V, 2.7 V ≤ V _b ≤ 4.0 V, C _b = 30 pF, R _b = 1.4 kΩ		100		100		100		100	ns
SOp output ^{Note 1}		$\begin{array}{l} 2.7 \ V \leq E V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		195		195		195		195	ns
		$\begin{split} 1.9 \ V &\leq E V_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$		483		483		483		483	ns
Slp setup time (to SCKp↓) ^{Note 2}	tsik1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	44		110		110		110		ns
		$\begin{array}{l} 2.7 \ V \leq E V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	44		110		110		110		ns
		$\begin{split} 1.9 \ V &\leq E V_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note } 3}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	110		110		110		110		ns
SIp hold time (from SCKp↓) ^{Note 2}	tksi1	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \end{array}$	19		19		19		19		ns
		$\begin{array}{l} 2.7 \ V \leq E V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 30 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	19		19		19		19		ns
		$\begin{split} 1.9 \ V &\leq E V_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 3}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	19		19		19		19		ns
Delay time from SCKp↑ to SOp	tkso1	$\begin{array}{l} 4.0 \; V \leq E V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 30 \; pF, \; R_b = 1.4 \; k\Omega \end{array}$		25		25		25		25	ns
output ^{Note 2}		2.7 V \leq EV _{DD} $<$ 4.0 V, 2.3 V \leq V _b \leq 2.7 V, C _b $=$ 30 pF, R _b $=$ 2.7 kΩ		25		25		25		25	ns
		1.9 V \leq EV _{DD} $<$ 3.3 V, 1.6 V \leq V _b \leq 2.0 V ^{Note 3} , C _b $=$ 30 pF, R _b $=$ 5.5 kΩ		25		25		25		25	ns

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EV}\text{DD0} = \text{EV}\text{DD1} \le \text{V}\text{DD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{ss0} = \text{EV}\text{ss1} = 0 \text{ V})$

(Notes, Caution and Remarks are listed on the next page.)

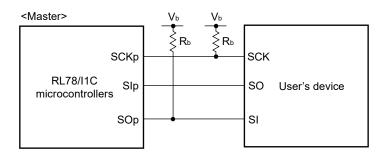
- **Notes 1.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.
 - 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
 - **3.** Use it with $EV_{DD} \ge V_b$.
 - 4. Either VDD or VBAT is selected by the battery backup function.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.

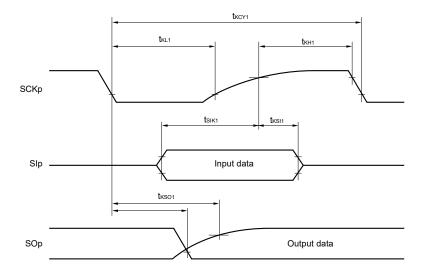
- **Remarks 1.** R_b[Ω]:Communication line (SCKp, SOp) pull-up resistance, C_b[F]: Communication line (SCKp, SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)
 - **3.** fMCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 12))

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

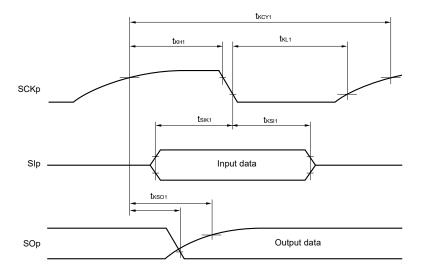


Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)





Simplified SPI (CSI) mode serial transfer timing (master mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0)



- Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remark** p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)



(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp ... external clock input)

($(T_A = -40 \text{ to } +85^{\circ}\text{C})$. 1.9 V ≤ EVDD0 =	$= EVDD1 \leq VDD^{Not}$	^{e 5} ≤ 5.5 V. Vss	= EVsso = EVss1 = () V)	(1/2)
		,				, '	· ··· —	,

Parameter	Symb ol		Conditions		h-speed Mode		/-speed Mode		/-power Mode	-	-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle	t ксү2	4.0 V ≤	24 MHz < fмск	14/ f мск		-		-		-		ns
time ^{Note 1}		EV _{DD} ≤ 5.5 V,	20 MHz < fмск ≤ 24 MHz	12/fмск		-		-		-		ns
		2.7 V ≤ V _b ≤ 4.0 V	8 MHz < fмск ≤ 20 MHz	10/fмск		_		_		_		ns
			4 MHz < fмск ≤ 8 MHz	8/f мск		16/ f мск		_		-		ns
			fмск ≤4 MHz	6/ f мск		10/f мск		10/f мск		10/fмск		ns
		2.7 V ≤	24 MHz < fмск	20/f мск		_		_		-		ns
		EV _{DD} < 4.0 V,	20 MHz < fмск ≤ 24 MHz	16/ f мск		-		-		-		ns
		2.3 V ≤ V _b ≤ 2.7 V	16 MHz < fмск ≤ 20 MHz	14/fмск		_		_		-		ns
		,	8 MHz < fмск ≤ 16 MHz	12/fмск		_		_		-		ns
			4 MHz < fмск ≤ 8 MHz	8/fмск		16/fмск		-		-		ns
			fмск ≤4 MHz	6/fмск		10/fмск		10/fмск		10/fмск		ns
		1.9 V ≤	24 MHz < fмск	48/f мск		_		_		-		ns
		EV _{DD} < 3.3 V,	20 MHz < fмск ≤ 24 MHz	36/fмск		-		_		-		ns
		1.6 V ≤ V _b ≤ 2.0 V ^{Note 2}	16 MHz < fмск ≤ 20 MHz	32/f мск		-		-		-		ns
		VN010 2	8 MHz < fмск ≤ 16 MHz	26/f мск		-		_		-		ns
			4 MHz < fмск ≤ 8 MHz	16/f мск		16/f мск		_		-		ns
			fмск ≤4 MHz	10/ f мск		10/ f мск		10/f мск		10/ f мск		ns
SCKp high- /low-level	tкн2, tк∟2		EV _{DD} ≤ 5.5 V, ⁄⊳ ≤ 4.0 V	tксү2/ 2 – 12		tксү2/ 2 – 50		tксү2/ 2 – 50		tксү2/ 2 – 50		ns
width			EV _{DD} < 4.0 V, ∕⊳ ≤ 2.7 V	tксү2/ 2 – 18		tксү2/ 2 – 50		tксү2/ 2 – 50		tксү2/ 2 – 50		ns
			EV _{DD} < 3.3 V, ∕ _b ≤ 2.0 V ^{Note 2}	tксү2/ 2 – 50		ns						
SIp setup time (to	tsik2		EV _{DD} ≤ 5.5 V, ⁄ _b ≤ 4.0 V ^{Note 2}	1/fмск + 20		1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SCKp↑) ^{Note 3}			EV _{DD} < 3.3 V, ∕ _b ≤ 2.0 V ^{Note 2}	1/fмск + 30		1/fмск + 30		1/fмск + 30		1/fмск + 30		ns
SIp hold time (from	tksi2		EV _{DD} ≤ 5.5 V, / _b ≤ 4.0 V ^{Note 2}	1/fмск + 31		1/fмск + 31		1/fмск + 31		1/fмск + 31		ns
SCKp↑) ^{Note 3}			EV _{DD} < 3.3 V, / _b ≤ 2.0 V ^{Note 2}	1/fмск + 31		1/fмск + 31		1/fмск + 31		1/fмск + 31		ns

(Notes, Caution and Remarks are listed on the next page.)



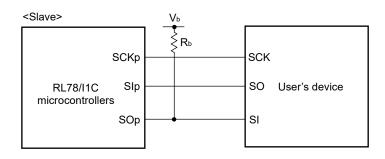
(8) Communication at different potential (1.8 V, 2.5 V, 3 V) (Simplified SPI (CSI) mode) (slave mode, SCKp ... external clock input)

Parameter	Symbol	Conditions	、 U	HS (high-speed main) Mode		LS (low-speed main) Mode		LP (low-power main) Mode		LV (low-voltage main) Mode	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Delay time from SCKp↓ to SOp output ^{Note 4}	tkso2	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 30 \ pF, \ R_b = 1.4 \ k\Omega \\ \hline 2.7 \ V \leq EV_{DD} < 4.0 \ V, \end{array}$		2/fмск + 120 2/fмск		2/fмск + 573 2/fмск		2/fмск + 573 2/fмск		2/fмск + 573 2/fмск	ns ns
ouipui		$2.3 V \le V_b \le 2.7 V,$ $C_b = 30 \text{ pF}, R_b = 2.7 \text{ k}\Omega$		+ 214		+ 573		+ 573		+ 573	
		$\begin{split} 1.9 \ V &\leq E V_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 30 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$		2/fмск + 573		2/fмск + 573		2/fмск + 573		2/fмск + 573	ns

Notes 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps

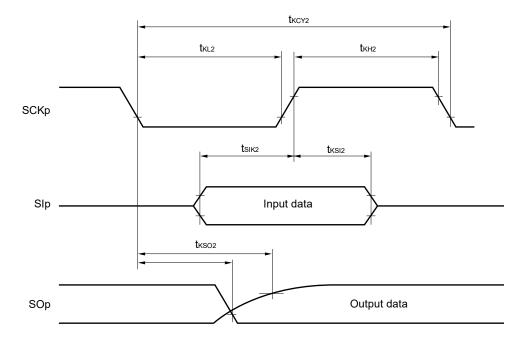
- **2.** Use it with $EV_{DD} \ge V_b$.
- **3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- **4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp hold time becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
- 5. Either V_DD or VBAT is selected by the battery backup function.
- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Simplified SPI (CSI) mode connection diagram (during communication at different potential)

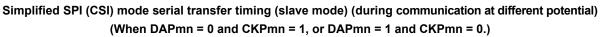


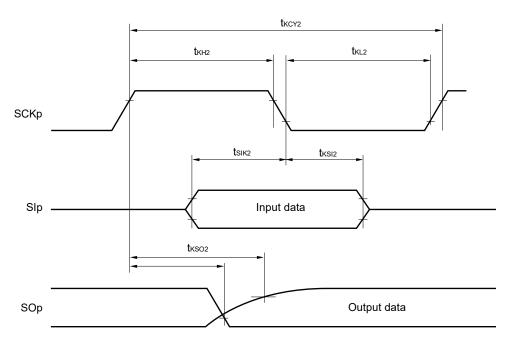
- **Remarks 1.** R_b[Ω]:Communication line (SOp) pull-up resistance, C_b[F]: Communication line (SOp) load capacitance, V_b[V]: Communication line voltage
 - p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1, 8)
 - fmck: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00, 02, 12))





Simplified SPI (CSI) mode serial transfer timing (slave mode) (during communication at different potential) (when DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1)





- Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (VDD tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remark** p: CSI number (p = 00, 10, 30), m: Unit number, n: Channel number (mn = 00, 02, 12), g: PIM and POM number (g = 0, 1, 8)

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I²C mode) (1/2)

$(T_A = -40 \text{ to } +85^{\circ}C, 1.9 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

Parameter	Symbol	Conditions		igh-speed n) Mode	•	v-speed Mode		w-power) Mode	-	/-voltage) Mode	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLr clock frequency	fscL	$\begin{array}{l} 4.0 \; V \leq E V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$		1000 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		1000 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$\begin{array}{l} 4.0 \; V \leq EV_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$		400 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$		400 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}		300 ^{Note 1}	kHz
Hold time when SCLr = "L"	t∟ow		475		1550		1550		1550		ns
		$\begin{array}{l} 2.7 \ V \leq E V_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	475		1550		1550		1550		ns
		$\begin{array}{l} 4.0 \; V \leq E V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$	1150		1150		1150		1150		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1150		1150		1150		1150		ns
		$\begin{split} 1.9 \ V &\leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	1150		1150		1150		1150		ns
Hold time when SCLr = "H"	tніgн	$\begin{array}{l} 4.0 \; V \leq E V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 50 \; pF, \; R_b = 2.7 \; k\Omega \end{array}$	245		610		610		610		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	200		610		610		610		ns
		$\begin{array}{l} 4.0 \; V \leq E V_{DD} \leq 5.5 \; V, \\ 2.7 \; V \leq V_b \leq 4.0 \; V, \\ C_b = 100 \; pF, \; R_b = 2.8 \; k\Omega \end{array}$	675		610		610		610		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	600		610		610		610		ns
		$\begin{split} 1.9 \ V &\leq E V_{DD} < 3.3 \ V, \\ 1.6 \ V &\leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b &= 100 \ pF, \ R_b = 5.5 \ k\Omega \end{split}$	610		610		610		610		ns

(Notes, Caution and Remarks are listed on the next page.)



Parameter	Symbol	Conditions		h-speed Mode	LS (low main)	•	``	/-power Mode	LV (low- main)	-	Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Data setup time (reception)	tsu:dat	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/f _{МСК} + 135 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{мск} + 190 ^{Note 3}		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/f _{МСК} + 135 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 100 \ pF, \ R_b = 2.8 \ k\Omega \end{array}$	1/f _{МСК} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	1/f _{МСК} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{мск} + 190 ^{Note 3}		ns
		$\begin{array}{l} 1.9 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_b \leq 2.0 \ V^{\text{Note 2}}, \\ C_b = 100 \ pF, \ R_b = 5.5 \ k\Omega \end{array}$	1/f _{МСК} + 190 ^{Note 3}		1/f _{MCK} + 190 ^{Note 3}		1/f _{МСК} + 190 ^{Note 3}		1/f _{мск} + 190 ^{Note 3}		ns
Data hold time (transmission)	thd:dat	$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	305	0	305	0	305	0	305	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 50 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	305	0	305	0	305	0	305	ns
		$\begin{array}{l} 4.0 \ V \leq EV_{DD} \leq 5.5 \ V, \\ 2.7 \ V \leq V_b \leq 4.0 \ V, \\ C_b = 100 \ pF, \ R_b = 2.8 \ k\Omega \end{array}$	0	355	0	355	0	355	0	355	ns
		$\begin{array}{l} 2.7 \ V \leq EV_{DD} < 4.0 \ V, \\ 2.3 \ V \leq V_b \leq 2.7 \ V, \\ C_b = 100 \ pF, \ R_b = 2.7 \ k\Omega \end{array}$	0	355	0	355	0	355	0	355	ns
		$\begin{array}{l} 1.9 \ V \leq EV_{DD} < 3.3 \ V, \\ 1.6 \ V \leq V_{b} \leq 2.0 \ V^{Note \ 2}, \\ C_{b} = 100 \ pF, \ R_{b} = 5.5 \ k\Omega \end{array}$	0	405	0	405	0	405	0	405	ns

(9) Communication at different potential (1.8 V, 2.5 V, 3 V) (simplified I²C mode) (2/2)

 $(T_A = -40 \text{ to } +85^{\circ}C, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{ Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

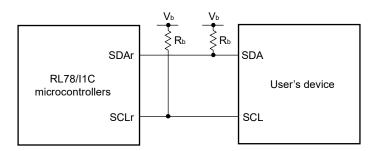
Notes 1. The value must also be equal to or less than $f_{MCK}/4$.

- **2.** Use it with $EV_{DD} \ge V_b$.
- 3. Set the fmck value to keep the hold time of SCLr = "L" and SCLr = "H".
- 4. Either V_{DD} or VBAT is selected by the battery backup function.
- Caution Select the TTL input buffer and the N-ch open drain output (V_{DD} tolerance) mode for the SDAr pin and the N-ch open drain output (V_{DD} tolerance) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

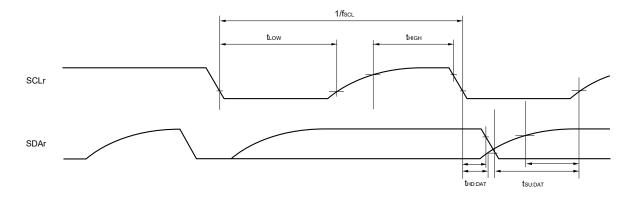
(Remarks are listed on the next page.)



Simplified I²C mode connection diagram (during communication at different potential)



Simplified I²C mode serial transfer timing (during communication at different potential)



- Caution Select the TTL input buffer and the N-ch open drain output (VDD tolerance) mode for the SDAr pin and the N-ch open drain output (VDD tolerance) mode for the SCLr pin by using port input mode register g (PIMg) and port output mode register g (POMg). For VIH and VIL, see the DC characteristics with TTL input buffer selected.
- **Remarks 1.** R_b[Ω]:Communication line (SDAr, SCLr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance, V_b[V]: Communication line voltage
 - **2.** r: IIC number (r = 00, 10, 30), g: PIM, POM number (g = 0, 1, 8)

 fMCK: Serial array unit operation clock frequency (Operating clock that is set with the serial clock select register m (SPSm) and the CKSmn bit of serial mode register mn (SMRmn).
 m: Unit number, n: Channel number (mn = 00, 02, 12))



2.5.2 Serial interface IICA

(1) I²C standard mode (1/2)

$(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	C	Conditions		h-speed Mode	•	/-speed Mode	``	/-power Mode		-voltage Mode	Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fsc∟	Standard mode:	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
		fc∟κ≥ 1 MHz	1.9 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
			1.8 V ≤ EV _{DD} ≤ 5.5 V	0	100	0	100	0	100	0	100	kHz
			1.7 V ≤ EV _{DD} ≤ 5.5 V	-	_	0	100	0	100	0	100	kHz
Setup time of	tsu:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
restart		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
condition		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	-	_	4.7		4.7		4.7		μs
Hold time ^{Note 1}	thd:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	-	-	4.0		4.0		4.0		μs
Hold time	t LOW	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
when SCLA0		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
= "L"		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	-	-	4.7		4.7		4.7		μs
Hold time	tніgн	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
when SCLA0		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
= "H"		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	-	-	4.0		4.0		4.0		μs
Data setup	tsu:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
time		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
(reception)		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	250		250		250		250		μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	-	-	250		250		250		μs
Data hold time	thd:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
(transmission)		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
Note 2		1.8 V ≤ E\	/ _{DD} ≤ 5.5 V	0	3.45	0	3.45	0	3.45	0	3.45	μs
		1.7 V ≤ E\	/ _{DD} ≤ 5.5 V	_	_	0	3.45	0	3.45	0	3.45	μs

(Notes and Remark are listed on the next page.)



(1) I^2C standard mode (2/2)

$(T_A = -40 \text{ to } +85^{\circ}C, 1.7 \text{ V} \le EV_{DD0} = EV_{DD1} \le V_{DD}^{Note 3} \le 5.5 \text{ V}, \text{ Vss} = EV_{SS0} = EV_{SS1} = 0 \text{ V})$

(14 10				- 010 1	, •00 -			•••			
Parameter	Symbol	Conditions	Conditions HS (high-speed LS (low-speed main) Mode main) Mode		•	LP (low-power main) Mode		LV (low-voltage main) Mode		Unit	
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
Setup time of	tsu:sto	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	4.0		4.0		4.0		4.0		μs
stop condition	1.9 V ≤ EV _{DD} ≤ 5.5 V	4.0		4.0		4.0		4.0		μs	
		$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$	4.0		4.0		4.0		4.0		μs
		1.7 V ≤ EV _{DD} ≤ 5.5 V	_	_	4.0		4.0		4.0		μs
Bus-free time	t BUF	$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$	4.7		4.7		4.7		4.7		μs
	1.9 V ≤ EV _{DD} ≤ 5.5 V	4.7		4.7		4.7		4.7		μs	
	$1.8 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$	4.7		4.7		4.7		4.7		μs	
		$1.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$	_	_	4.7		4.7		4.7		μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

3. Either V_{DD} or VBAT is selected by the battery backup function.

Standard mode: C_b = 400 pF, R_b = 2.7 k Ω



Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

(2) I²C fast mode

$(T_A = -40 \text{ to } +85^{\circ}C, 1.9 \text{ V} \le \text{EV}_{DD0} = \text{EV}_{DD1} \le \text{V}_{DD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{ Vss} = \text{EV}_{SS0} = \text{EV}_{SS1} = 0 \text{ V})$

Parameter	arameter Symbol		Conditions		Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		LP (low-power main) Mode		LV (low-voltage main) Mode	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.			
SCLA0 clock frequency	fsc∟	Fast mode:	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	400	0	400	-	-	0	400	kHz		
		fc∟κ≥ 3.5 MHz	1.9 V ≤ EV _{DD} ≤ 5.5 V	0	400	0	400	-	-	0	400	kHz		
Setup time of	tsu:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0.6		0.6		_	-	0.6		μs		
restart condition		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs		
Hold time ^{Note 1}	thd:sta	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs		
	1.9 V ≤ E		/ _{DD} ≤ 5.5 V	0.6		0.6		_	-	0.6		μs		
Hold time	Hold time t⊾ow		$2.7 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$			1.3		_	-	1.3		μs		
when SCLA0 = "L"	$1.9 \text{ V} \leq \text{EV}_{\text{DD}} \leq 5.5 \text{ V}$		1.3		1.3		_	-	1.3		μs			
Hold time	tнigн	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs		
when SCLA0 = "H"		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	0.6		0.6		-	-	0.6		μs		
Data setup	tsu:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	100		100		_	-	100		ns		
time (reception)		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	100		100		-	-	100		ns		
Data hold time	thd:dat	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	0	0.9	0	0.9	_	-	0	0.9	μs		
(transmission) Note 2		1.9 V ≤ E\	/ _{DD} ≤ 5.5 V	0	0.9	0	0.9	-	-	0	0.9	μs		
Setup time of	tsu:sto	2.7 V ≤ E\	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			0.6		_	_	0.6		μs		
stop condition		$1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$		0.6		0.6		_	-	0.6		μs		
Bus-free time	t BUF	2.7 V ≤ E\	/ _{DD} ≤ 5.5 V	1.3		1.3		_	-	1.3		μs		
		1.9 V ≤ E\	$1.9 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			1.3		-	_	1.3		μs		

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

2. The maximum value (MAX.) of the during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

3. Either V_{DD} or VBAT is selected by the battery backup function.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode: $C_b = 320 \text{ pF}, R_b = 1.1 \text{ k}\Omega$



(3) I²C fast mode plus

$(T_A = -40 \text{ to } +85^{\circ}C, 2.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

(1 - 40 t)		• = = • •			20.0	,	LV330 -		••,			
Parameter	Symbol	Conditions		Conditions HS (high-speed LS (low-speed main) Mode main) Mode		•	LP (low-power main) Mode		LV (low-voltage main) Mode		Unit	
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	fscL	Fast mode plus: fc⊥ĸ ≥ 10 MHz	2.7 V ≤ EV _{DD} ≤ 5.5 V	0	1000	_	_	_	_	_	_	kHz
Setup time of restart condition	tsu:sta	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		-	_	_	_	-	_	μs
Hold time ^{Note 1}	thd:sta	2.7 V ≤ E	$2.7 \text{ V} \le \text{EV}_{\text{DD}} \le 5.5 \text{ V}$			-	-	-	-	-	-	μs
Hold time when SCLA0 = "L"	t∟ow	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.5		-	_	_	_	-	_	μs
Hold time when SCLA0 = "H"	tніgн	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		_	_	_	_	-	_	μs
Data setup time (reception)	tsu:dat	2.7 V ≤ E	V _{DD} ≤ 5.5 V	50		_	_	_	_	-	_	ns
Data hold time (transmission) ^{Note 2}	thd:dat	2.7 V ≤ E	Vdd ≤ 5.5 V	0	0.5	-	-	-	-	-	-	μs
Setup time of stop condition	tsu:sto	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.26		-	-	-	-	-	-	μs
Bus-free time	t BUF	2.7 V ≤ E	V _{DD} ≤ 5.5 V	0.5		_	_	_	_	-	_	μs

Notes 1. The first clock pulse is generated after this period when the start/restart condition is detected.

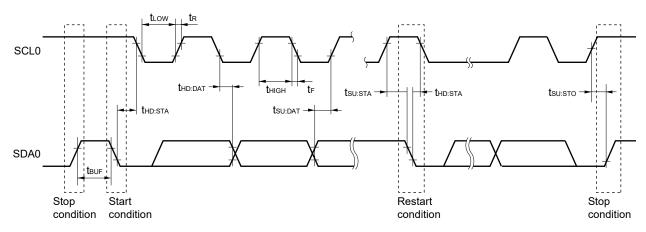
2. The maximum value (MAX.) of the:DAT is during normal transfer and a clock stretch state is inserted in the ACK (acknowledge) timing.

3. Either VDD or VBAT is selected by the battery backup function.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Fast mode plus: C_b = 120 pF, R_b = 1.1 k Ω

IICA serial transfer timing



2.6 Analog Characteristics

2.6.1 A/D converter characteristics

(1) When reference voltage (+) = AVREFP/ANIO (ADREFP1 = 0, ADREFP0 = 1), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pins: ANI2 to ANI5 and internal reference voltage

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le V_{DD}^{Note 3} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V}, \text{ reference voltage (+)} = AV_{REFP}, \text{ reference voltage (-)} = AV_{REFM} = 0 \text{ V})$

Parameter	Symbol	Co	onditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution AV _{REFP} = V _{DD}	$1.9 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$		1.2	±5.0	LSB
Conversion time	t CONV	10-bit resolution	$3.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.125		39	μs
			$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.1875		39	μs
			$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution AV _{REFP} = V _{DD}	$1.9 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
Full-scale error ^{Notes 1, 2}	Efs	10-bit resolution AV _{REFP} = V _{DD}	$1.9 \text{ V} \leq \text{AV}_{\text{REFP}} \leq 5.5 \text{ V}$			±0.35	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±3.5	LSB
Differential linearity error ^{Note 1}	DLE	10-bit resolution AV _{REFP} = V _{DD}	1.9 V ≤ AV _{REFP} ≤ 5.5 V			±2.0	LSB
Reference voltage (+)	AVREFP			1.9		VDD	V
Analog input voltage	VAIN			0		AVREFP	V
	VBGR	Select internal referen 2.4 V ≤ V _{DD} ≤ 5.5 V, H	nce voltage output HS (high-speed main) mode	1.38	1.45	1.5	V

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.



(2) When reference voltage (+) = V_{DD} (ADREFP1 = 0, ADREFP0 = 0), reference voltage (-) = V_{SS} (ADREFM = 0), target pins: ANI0 to ANI5 and internal reference voltage

Parameter	Symbol		Conditions	MIN.	TYP.	MAX.	Unit
Resolution	RES			8		10	bit
Overall error ^{Note 1}	AINL	10-bit resolution	$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$		1.2	±10.5	LSB
Conversion time	t CONV	10-bit resolution	$3.6 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	2.125		39	μs
			$2.7 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	3.1875		39	μs
			$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	10-bit resolution	$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±0.85	%FSR
Full-scale error ^{Notes 1, 2}	Efs	10-bit resolution	$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±0.85	%FSR
Integral linearity error ^{Note 1}	ILE	10-bit resolution	$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±4.0	LSB
Differential linearity errorNote 1	DLE	10-bit resolution	$1.9 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±2.0	LSB
Analog input voltage	VAIN			0		VDD	V
	Vbgr		ence voltage output, , HS (high-speed main) mode	1.38	1.45	1.5	V

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V}, \text{ reference voltage (+)} = \text{V}_{DD}^{\text{Note 3}}, \text{ reference voltage (-)} = \text{Vss})$

Notes 1. Excludes quantization error (±1/2 LSB).

- 2. This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.
- Caution When using reference voltage (+) = VDD, taking into account the voltage drop due to the effect of the power switching circuit of the battery backup function and use the A/D conversion result. In addition, enter HALT mode during A/D conversion and set VDD port to input.
- (3) When reference voltage (+) = Internal reference voltage (ADREFP1 = 1, ADREFP0 = 0), reference voltage (-) = AVREFM/ANI1 (ADREFM = 1), target pins: ANI0, ANI2 to ANI5

(T_A = -40 to +85°C, 2.4 V \leq V_{DD}^{Note 3} \leq 5.5 V, V_{SS} = 0 V, reference voltage (+) = V_{BGR}, reference voltage (-) = AV_{REFM} = 0 V, HS (high-speed main) mode)

Parameter	Symbol		MIN.	TYP.	MAX.	Unit	
Resolution	RES				8		bit
Conversion time	t CONV	8-bit resolution	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$	17		39	μs
Zero-scale error ^{Notes 1, 2}	Ezs	8-bit resolution	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±0.60	%FSR
Integral linearity error ^{Note 1}	ILE	8-bit resolution	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±2.0	LSB
Differential linearity error ^{Note 1}	DLE	8-bit resolution	$2.4 \text{ V} \leq \text{V}_{\text{DD}} \leq 5.5 \text{ V}$			±1.0	LSB
Reference voltage (+)	VBGR			1.38	1.45	1.5	V
Analog input voltage	VAIN			0		Vbgr	V

Notes 1. Excludes quantization error (±1/2 LSB).

- **2.** This value is indicated as a ratio (%FSR) to the full-scale value.
- 3. Either V_{DD} or VBAT is selected by the battery backup function.



2.6.2 24-bit $\Delta\Sigma$ A/D converter characteristics

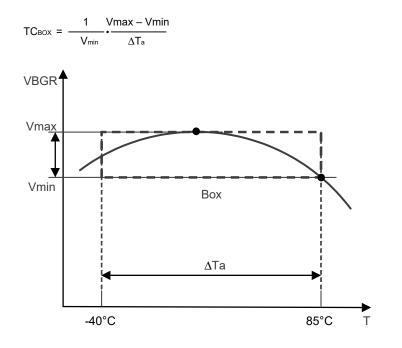
(1) Reference voltage

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.4 \text{ V} \le \text{V}_{DD}^{Note 1} \le 5.5 \text{ V}, \text{ V}_{SS} = \text{AV}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Internal reference voltage	VAVRTO			0.8		V
Temperature coefficient for internal reference voltage Note 2	ТСвох	0.47 μF capacitor connected to AREGC, AVRT, and AVCM pins		10		ppm/°C

Notes 1. Either V_{DD} or VBAT is selected by the battery backup function.

2. This is as stipulated by the BOX method.





(2) Analog input

(TA = -40 to +85°C, 2.4 V \leq VDD^{Note} \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Input voltage range	VAIN	x1 gain	-500		500	mV
(differential voltage)		x2 gain	-250		250	
		x4 gain	-125		125	
		x8 gain	-62.5		62.5	
		x16 gain	-31.25		31.25	
		x32 gain	-15.625		15.625	
Input gain	ainGAIN	x1 gain		1		Times
		x2 gain		2		
		x4 gain		4		
		x8 gain		8		
		x16 gain		16		
		x32 gain		32		
Input impedance	ainRIN	Differential voltage	150	360		kΩ
		Single-ended voltage	100	240		

 $\label{eq:Note} \mbox{ Bither V}_{\mbox{DD}} \mbox{ or VBAT is selected by the battery backup function.}$



(3) 4 kHz sampling mode

(T_A = -40 to +85°C, 2.4 V \leq V_{DD}^{Note} \leq 5.5 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Operation clock	fdsad	fx oscillation clock, input external clock or high- speed on-chip oscillator clock is used		12		MHz
Sampling frequency	fs			3906.25		Hz
Oversampling frequency	fos			1.5		MHz
Output data rate	Tdata			256		μs
Data width	RES			24		bit
SNDR	SNDR	x1 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)		80		dB
		x16 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	69	74		
		x32 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	65	69		
Passband (low pass band) fc	f _{Chpf}	At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 00		0.607		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 01		1.214		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 10		2.429		Hz
		At –3 dB (phase in high pass filter not adjusted) Bits 7 and 6 of DSADHPFCR register (DSADCOF1, DSADCOF0) = 11		4.857		Hz
In-band ripple 1	rp1	45 Hz to 55 Hz @50 Hz 54 Hz to 66 Hz @60 Hz	-0.01		0.01	dB
In-band ripple 2	rp2	45 Hz to 275 Hz @50 Hz 54 Hz to 330 Hz @60 Hz	-0.1		0.1	
In-band ripple 3	rp3	45 Hz to 1100 Hz @50 Hz 54 Hz to 1320 Hz @60 Hz	-0.1		0.1	
Passband (high pass band)	fclpf	–3 dB		1672		Hz
Stopband (high pass band)	fatt	–80 dB		2545		Hz
Out-band attenuation	ATT1	fs	-80			dB
	ATT2	2 fs	-80			dB



(4) 2 kHz sampling mode

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Operation clock	fdsad	fx oscillation clock, input external clock or high- speed on-chip oscillator clock is used		12		MHz
Sampling frequency	fs			1953.125		Hz
Oversampling frequency	fos			0.75		MHz
Output data rate	Трата			512		μs
Data width	RES			24		bit
SNDR	SNDR	x1 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)		80		dB
		x16 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	69	74		
		x32 gain High-speed system clock is selected as operating clock of 24-bit $\Delta\Sigma$ A/D converter (bit 0 of PCKC register (DSADCK) = 1)	65	69		
Passband (low pass band)	f Chpf	At –3 dB (phase in high pass filter not adjusted)		0.303		Hz
In-band ripple 1	rp1	45 Hz to 55 Hz @50 Hz 54 Hz to 66 Hz @60 Hz	-0.01		0.01	dB
In-band ripple 2	rp2	45 Hz to 275 Hz @50 Hz 54 Hz to 330 Hz @60 Hz	-0.1		0.1	
In-band ripple 3	rp3	45 Hz to 660 Hz @50 Hz 54 Hz to 550 Hz @60 Hz	-0.1		0.1	
Passband (high pass band)	f _{Clpf}	–3 dB		836		Hz
Stopband (high pass band)	fatt	–80 dB		1273		Hz
Out-band attenuation	ATT1	fs	-80			dB
	ATT2	2 fs	-80			dB

Note Either V_{DD} or VBAT is selected by the battery backup function.

2.6.3 Temperature sensor 2 characteristics

(T_A = -40 to +85°C, 2.4 V \leq V_{DD}^{Note 2} \leq 5.5 V, V_{SS} = 0 V, HS (high-speed main) mode)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor 2 output voltage	Vout			0.67		V
Temperature coefficient	Fvtmps2	Temperature sensor that depends on the temperature	-11.7	-10.7	-9.7	mV/°C
Operation stabilization wait time ^{Note 1}	t tmpon	Operable		15	50	μs
	tтмрснg	Switching mode		5	15	μs

Notes 1. Time to drop to output stable value ±5LSB (±7 mV) or less.

2.6.4 POR circuit characteristics

$(T_A = -40 \text{ to } +85^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VPOR	When power supply rises ^{Note 1}	1.47	1.51	1.55	V
	VPDR	When power supply falls ^{Note 2}	1.46	1.50	1.54	V

Notes 1. Be sure to maintain the reset state until the power supply voltage rises over the minimum V_{DD} value in the operating voltage range specified in **2.4 AC Characteristics**, by using the voltage detector or external reset pin.

2. If the power supply voltage falls while the voltage detector is off, be sure to either shift to STOP mode or execute a reset by using the voltage detector or external reset pin before the power supply voltage falls below the minimum operating voltage specified in 2.4 AC Characteristics.

2.6.5 LVD circuit characteristics

LVD Detection Voltage of Reset Mode and Interrupt Mode

 $(T_A = -40 \text{ to } +85^{\circ}C, V_{PDR} \le V_{DD}^{Note} \le 5.5 \text{ V}, \text{ Vss} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVD0	When power supply rises	3.98	4.06	4.24	V
		When power supply falls	3.90	3.98	4.16	V
	VLVD1	When power supply rises	3.68	3.75	3.92	V
		When power supply falls	3.60	3.67	3.84	V
	VLVD2	When power supply rises	3.07	3.13	3.29	V
		When power supply falls	3.00	3.06	3.22	V
	VLVD3	When power supply rises	2.96	3.02	3.18	V
		When power supply falls	2.90	2.96	3.12	V
	VLVD4	When power supply rises	2.86	2.92	3.07	V
		When power supply falls	2.80	2.86	3.01	V
	VLVD5	When power supply rises	2.76	2.81	2.97	V
		When power supply falls	2.70	2.75	2.91	V
	VLVD6	When power supply rises	2.66	2.71	2.86	V
		When power supply falls	2.60	2.65	2.80	V
	VLVD7	When power supply rises	2.56	2.61	2.76	V
		When power supply falls	2.50	2.55	2.70	V
	VLVD8	When power supply rises	2.45	2.50	2.65	V
		When power supply falls	2.40	2.45	2.60	V
	VLVD9	When power supply rises	2.05	2.09	2.23	V
		When power supply falls	2.00	2.04	2.18	V
	VLVD10	When power supply rises	1.94	1.98	2.12	V
		When power supply falls	1.90	1.94	2.08	V
	VLVD11	When power supply rises	1.84	1.88	2.01	V
		When power supply falls	1.80	1.84	1.97	V
	VLVD12	When power supply rises	1.74	1.77	1.81	V
		When power supply falls	1.70	1.73	1.77	V
Minimum pulse width	t∟w		300			μs
Detection delay time					300	μs



LVD Detection Voltage of Interrupt & Reset Mode

Parameter	Symbol		Con	MIN.	TYP.	MAX.	Unit	
Detection voltage	VLVD8	VPOC2,	VPOC1, VPOC0 = 0,	1.80	1.84	1.97	V	
	VLVD7		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	1.94	1.98	2.12	V
			(+0.1 V)	Falling interrupt voltage	1.90	1.94	2.08	V
	VLVD6		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.05	2.09	2.23	V
			(+0.2 V)	Falling interrupt voltage	2.00	2.04	2.18	V
	VLVD1		LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.07	3.13	3.29	V
			(+1.2 V)	Falling interrupt voltage	3.00	3.06	3.22	V
Vlvd8 Vlvd7	VPOC2,	VPOC1, VPOC0 = 0,	1, 0, falling reset voltage	2.40	2.45	2.60	V	
	VLVD7		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.56	2.61	2.76	V
			F	Falling interrupt voltage	2.50	2.55	2.70	V
	VLVD6		LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.66	2.71	2.86	V
				Falling interrupt voltage	2.60	2.65	2.80	V
	VLVD1	LVIS1, LVIS0 = 0, 0		Rising release reset voltage	3.68	3.75	3.92	V
				Falling interrupt voltage	3.60	3.67	3.84	V
	VLVD5	VPOC2,	VPOC1, VPOC0 = 0,	1, 1, falling reset voltage	2.70	2.75	2.91	V
	VLVD4		LVIS1, LVIS0 = 1, 0	Rising release reset voltage	2.86	2.92	3.07	V
				Falling interrupt voltage	2.80	2.86	3.01	V
	VLVD3]	LVIS1, LVIS0 = 0, 1	Rising release reset voltage	2.96	3.02	3.18	V
				Falling interrupt voltage	2.90	2.96	3.12	V
	VLVD0	1	LVIS1, LVIS0 = 0, 0	Rising release reset voltage	3.98	4.06	4.24	V
				Falling interrupt voltage	3.90	3.98	4.16	V

 $\label{eq:Note} \mbox{ Bither V}_{\mbox{DD}} \mbox{ or VBAT is selected by the battery backup function.}$

2.6.6 Power supply voltage rising slope characteristics

$(T_A = -40 \text{ to } +85^{\circ}C, V_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDDR				54	V/ms
	SVRTCR					

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until V_{DD} reaches the operating voltage range shown in 2.4 AC Characteristics.

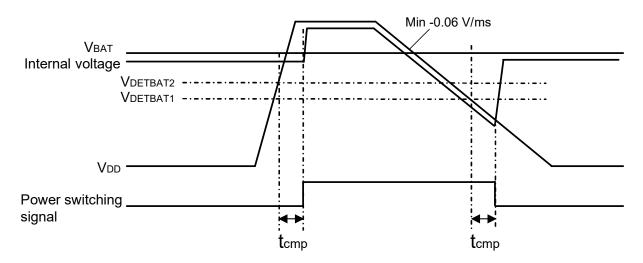


2.7 Battery Backup Function

2.7.1 Power supply switching characteristics

(T_A = -40 to +85°C, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Power switching detection voltage	Vdetbat1	$V_{DD} \rightarrow VBAT$ $V_{BAT} \leq 3.6 V$	2.09	2.18	2.26	V
	VDETBAT2	$VBAT \rightarrow V_{DD}$ $V_{BAT} \leq 3.6 V$	2.19	2.28	2.36	V
V _{DD} fall slope	SVDDF		-0.06			V/ms
Response time of power switch detector	t _{cmp}	V _{BAT} ≤ 3.6 V			500	μs

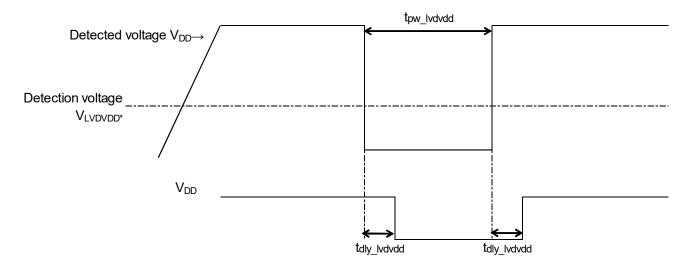




2.7.2 VDD pin voltage detection characteristics

Parameter	Symbol	LVDVDD[2:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVDD0	000	Rising	2.40	2.53	2.65	V
			Falling	2.33	2.46	2.58	V
	VLVDVDD1	001	Rising	2.60	2.74	2.86	V
			Falling	2.53	2.67	2.79	V
	VLVDVDD2	010	Rising	2.79	2.94	3.07	V
			Falling	2.73	2.87	2.99	V
	VLVDVDD3	011	Rising	3.00	3.15	3.28	V
			Falling	2.93	3.08	3.21	V
	VLVDVDD4	100	Rising	3.30	3.46	3.60	V
			Falling	3.23	3.39	3.52	V
	VLVDVDD5	101	Rising	3.59	3.77	3.91	V
			Falling	3.53	3.70	3.84	V
Minimum pulse width	tpw_lvdvdd	_	_	300			μs
Detection delay time	tdly_lvdvdd	_	_			300	μs

(TA = -40 to +85°C, 1.9 V \leq VDD^{Note} \leq 5.5 V, Vss = 0 V)

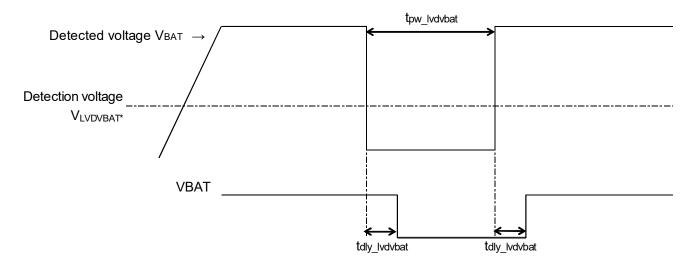




2.7.3 VBAT pin voltage detection characteristics

Parameter	Symbol	LVDVBAT[2:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVBAT0	000	Rising	1.99	2.11	2.22	V
			Falling	1.94	2.05	2.16	V
	VLVDVBAT1	001	Rising	2.09	2.21	2.32	V
			Falling	2.03	2.15	2.26	V
	VLVDVBAT2	010	Rising	2.20	2.32	2.43	V
			Falling	2.14	2.26	2.37	V
	VLVDVBAT3	011	Rising	2.29	2.42	2.53	V
			Falling	2.23	2.36	2.47	V
	VLVDVBAT4	100	Rising	2.38	2.52	2.64	V
			Falling	2.33	2.46	2.58	V
	VLVDVBAT5	101	Rising	2.48	2.62	2.74	V
			Falling	2.42	2.56	2.68	V
	VLVDVBAT6	110	Rising	2.59	2.73	2.86	V
			Falling	2.53	2.67	2.79	V
Minimum pulse width	tpw_lvdvbat	_	_	300			μs
Detection delay time	tdly_lvdvbat	_	_			300	μs

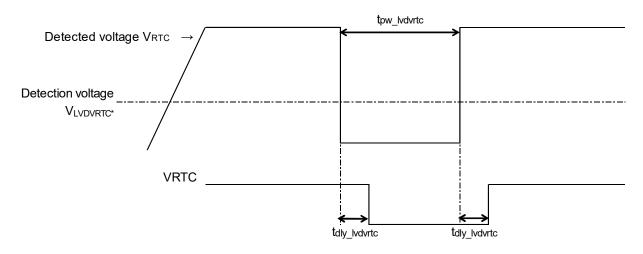
(TA = -40 to +85°C, 1.9 V \leq VDD^{Note} \leq 5.5 V, Vss = 0 V)



2.7.4 VRTC pin voltage detection characteristics

Parameter	Symbol	LVDVRTC[1:0]	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDVRTC0	00	Rising	2.16	2.22	2.28	V
			Falling	2.10	2.16	2.22	V
	VLVDVRTC1	VLVDVRTC1 01	Rising	2.36	2.43	2.50	V
			Falling	2.30	2.37	2.44	V
	Vlvdvrtc2 10 R	Rising	2.56	2.63	2.70	V	
			Falling	2.50	2.57	2.64	V
	VLVDVRTC3	11	Rising	2.76	2.76 2.84 2.92	2.92	V
			Falling	2.70	2.78	2.86	V
Minimum pulse width	tpw_lvdvrtc	_	_	300			μs
Detection delay time	tdly_lvdvrtc	_	_			300	μs

(TA = -40 to +85°C, 1.9 V \leq VDD^{Note} \leq 5.5 V, Vss = 0 V)

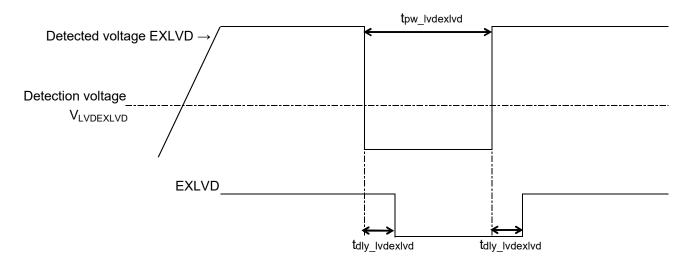




2.7.5 EXLVD pin voltage detection

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{Note} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	VLVDEXLVD	Rising	1.25	1.33	1.41	V
		Falling	1.20	1.28	1.36	V
Minimum pulse width	tpw_lvdexlvd	_	300			μs
Detection delay time	tdly_lvdexlvd	_			300	μs
Pin resistor	f in_exlvd	LVDEXLVDEN = 1		34		MΩ





2.8 LCD Characteristics

2.8.1 Resistance division method

(1) Static display mode

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.0		$V_{\text{DD}}^{\text{Note}}$	V

Note Either V_{DD} or VBAT is selected by the battery backup function.

(2) 1/2 bias method, 1/4 bias method

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, V_{L4} \text{ (MIN.)} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{Note} \le 5.5 \text{ V}, \text{ Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.7		VDD ^{Note}	V

Note Either V_{DD} or VBAT is selected by the battery backup function.

(3) 1/3 bias method

$(T_{A} = -40 \text{ to } +85^{\circ}\text{C}, \text{ V}_{L4} \text{ (MIN.)} \leq \text{EVDD0} = \text{EVDD1} \leq \text{VDD}^{\text{Note}} \leq 5.5 \text{ V}, \text{ Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.5		$V_{\text{DD}}^{\text{Note}}$	V



2.8.2 Internal voltage boosting method

(1) 1/3 bias method

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EV}_{\text{DD}} = \text{EV}_{\text{DD}} \le \text{V}_{\text{DD}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}_{\text{SS0}} = \text{EV}_{\text{SS1}} = 0 \text{ V})$

Parameter	Symbol	Cond	litions	MIN.	TYP.	MAX.	Unit	
LCD output voltage variation range	VL1	C1 to C4 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V	
		= 0.47 µF	VLCD = 05H	0.95	1.05	1.13	V	
			VLCD = 06H	1.00	1.10	1.18	V	
			VLCD = 07H	1.05	1.15	1.23	V	
			VLCD = 08H	1.10	1.20	1.28	V	
			VLCD = 09H	1.15	1.25	1.33	V	
			VLCD = 0AH	1.20	1.30	1.38	V	
			VLCD = 0BH	1.25	1.35	1.43	V	
			VLCD = 0CH	1.30	1.40	1.48	V	
			VLCD = 0DH	1.35	1.45	1.53	V	
			VLCD = 0EH	1.40	1.50	1.58	V	
			VLCD = 0FH	1.45	1.55	1.63	V	
				VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V	
			VLCD = 12H	1.60	1.70	1.78	V	
			VLCD = 13H	1.65	1.75	1.83	V	
Doubler output voltage	VL2	C1 to C4 ^{Note 1} =	0.47 μF	2 VL1-0.10	2 VL1	2 VL1	V	
Tripler output voltage	VL4	C1 to C4 ^{Note 1} =	0.47 µF	3 VL1-0.15	3 VL1	3 VL1	V	
Reference voltage setup time ^{Note 2}	tvwait1			5			ms	
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C4 ^{Note 1} =	0.47 µF	500			ms	

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

- C2: A capacitor connected between V_{L1} and GND
- C3: A capacitor connected between V_{L2} and GND
- C4: A capacitor connected between V_{L4} and GND
- C1 = C2 = C3 = C4 = 0.47 µF±30%
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- 4. Either V_{DD} or VBAT is selected by the battery backup function.



(2) 1/4 bias method

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.7 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

Parameter	Symbol	Cor	nditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	V _{L1}	C1 to C5 ^{Note 1}	VLCD = 04H	0.90	1.00	1.08	V
		= 0.47 µF	VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
Doubler output voltage	VL2	C1 to C5 ^{Note 1} =	0.47 µF	2 VL1-0.08	2 VL1	2 VL1	V
Tripler output voltage	VL3	C1 to C5 ^{Note 1} =	0.47 µF	3 VL1-0.12	3 VL1	3 VL1	V
Quadruply output voltage	VL4	C1 to C5 ^{Note 1} =	0.47 µF	4 VL1-0.16	4 VL1	4 V _{L1}	V
Reference voltage setup time ^{Note 2}	tvwait1			5			ms
Voltage boost wait time ^{Note 3}	tvwait2	C1 to C5 ^{Note 1} =	0.47 µF	500			ms

Notes 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

- C2: A capacitor connected between VL1 and GND
- C3: A capacitor connected between V_{L2} and GND
- C4: A capacitor connected between V_{L3} and GND
- C5: A capacitor connected between V_{L4} and GND
- C1 = C2 = C3 = C4 = C5 = 0.47 µF±30%
- 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).
- 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).
- **4.** Either VDD or VBAT is selected by the battery backup function.



2.8.3 Capacitor split method

(1) 1/3 bias method

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 2.2 \text{ V} \le \text{EV}\text{DD0} = \text{EV}\text{DD1} \le \text{V}\text{DD}^{\text{Note 3}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{ss0} = \text{EV}\text{ss1} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
VL4 voltage	VL4	C1 to C4 = 0.47 $\mu F^{Note 2}$		$V_{DD}^{Note 3}$		V
VL2 voltage	VL2	C1 to C4 = 0.47 µF ^{Note 2}	2/3 V _{L4} 0.1	2/3 VL4	2/3 V _{L4} + 0.1	V
V _{L1} voltage	V _{L1}	C1 to C4 = 0.47 µF ^{Note 2}	1/3 V∟4– 0.1	1/3 VL4	1/3 V _{L4} + 0.1	V
Capacitor split wait time ^{Note 1}	t vwait		100			ms

Notes 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

2. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between VL1 and GND

C3: A capacitor connected between V_{L2} and GND

C4: A capacitor connected between V_{L4} and GND

C1 = C2 = C3 = C4 = 0.47 µF±30%

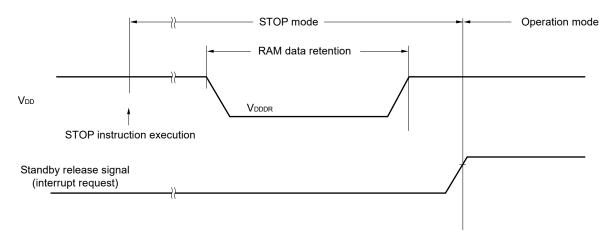


2.9 RAM Data Retention Characteristics

(T_A = -40 to +85°C)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 ^{Note}		5.5	V

Note The value depends on the POR detection voltage. When the voltage drops, the data in RAM are retained until a POR is applied, but are not retained following a POR.



2.10 Flash Memory Programming Characteristics

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{V}_{DD}^{\text{Note 4}} \le 5.5 \text{ V}, \text{ V}_{SS} = 0 \text{ V})$

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
System clock frequency	fclĸ	$1.9 \text{ V} \leq \text{V}_{\text{DD}}^{\text{Note 4}} \leq 5.5 \text{ V}$	1		24	MHz
Number of code flash rewrites ^{Notes 1, 2, 3}	Cerwr	Retained for 20 years TA = 85°C	1,000			Times
Number of data flash rewrites ^{Notes 1, 2, 3}		Retained for 1 year		1,000,000		
		TA = 25°C				
		Retained for 5 years	100,000			
		TA = 85°C				
		Retained for 20 years	10,000			
		TA = 85°C				

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

- 2. When using flash memory programmer and Renesas Electronics self programming library
- 3. This characteristic indicates the flash memory characteristic and based on Renesas Electronics reliability test.
- **4.** Either VDD or VBAT is selected by the battery backup function.

2.11 Dedicated Flash Memory Programmer Communication (UART)

$(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EVDD0} = \text{EVDD1} \le \text{VDD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EVss0} = \text{EVss1} = 0 \text{ V})$

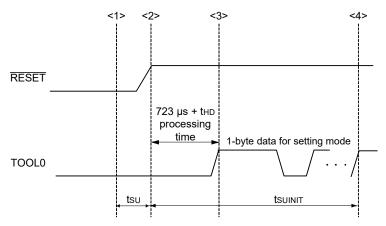
Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps



2.12 Timing Specs for Switching Flash Memory Programming Modes

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Time to complete the communication for the initial setting after the external reset is released	tsuinit	POR and LVD reset must be released before the external reset is released.			100	ms
Time to release the external reset after the TOOL0 pin is set to the low level	ts∪	POR and LVD reset must be released before the external reset is released.	10			μs
Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)	tно	POR and LVD reset must be released before the external reset is released.	1			ms

 $(T_A = -40 \text{ to } +85^{\circ}\text{C}, 1.9 \text{ V} \le \text{EV}\text{DD} = \text{EV}\text{DD} \le \text{V}\text{DD}^{\text{Note}} \le 5.5 \text{ V}, \text{Vss} = \text{EV}\text{sso} = \text{EV}\text{sso} = 0 \text{ V})$



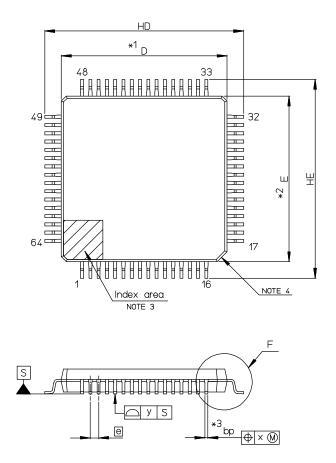
- <1> The low level is input to the TOOL0 pin.
- <2> The external reset is released (POR and LVD reset must be released before the external reset is released.).
- <3> The TOOL0 pin is set to the high level.
- <4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.
- **Remark** tsuinit: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.
 - t_{SU} : Time to release the external reset after the TOOL0 pin is set to the low level.
 - the: Time to hold the TOOL0 pin at the low level after the external reset is released (excluding the processing time of the firmware to control the flash memory)

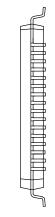
PACKAGE DRAWINGS 3.

3.1 64-pin Products

R5F10NLEDFB, R5F10NLGDFB, R5F11TLEDFB, R5F11TLGDFB

<r></r>	JEITA Package Code	RENESAS Code	Previous Code	MASS[Typ.]
	P-LFQFP64-10x10-0.50	PLQP0064KB-C		0.3g



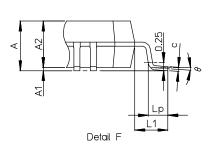


NOTE)

1. 2. 3.

DIMENSIONS '*1' AND '*2' DO NOT INCLUDE MOLD FLASH. DIMENSION '*3' DOES NOT INCLUDE TRIM OFFSET. PIN 1 VISUAL INDEX FEATURE MAY VARY, BUT MUST BE LOCATED WITHIN THE HATCHED AREA. CHAMFERS AT CORNERS ARE OPTIONAL; SIZE MAY VARY. 4.

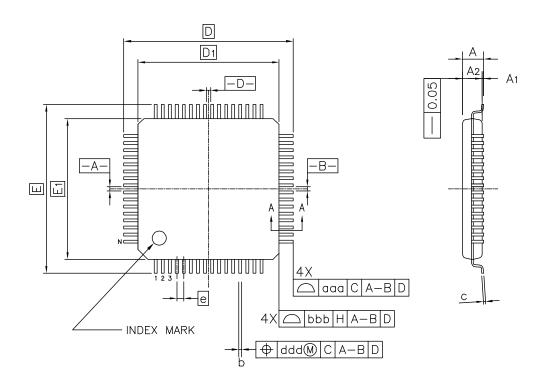
Reference	Dimension in Millimeters		
Symbol	Min	Nom	Max
D	9.9	10.0	10.1
E	9.9	10.0	10.1
A2		1.4	
HD	11.8	12.0	12.2
HE	11.8	12.0	12.2
А			1.7
A1	0.05		0.15
bp	0.15	0.20	0.27
С	0.09		0.20
θ	θ Ο "		8"
е		0.5	
×			0.08
У			80.0
Lp	0.45	0.6	0.75
L1		1.0	

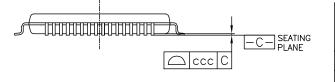


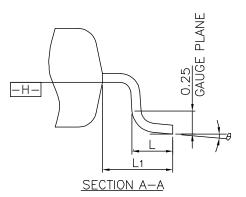


<R>

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP064-10x10-0.50	PLQP0064KL-A	0.36





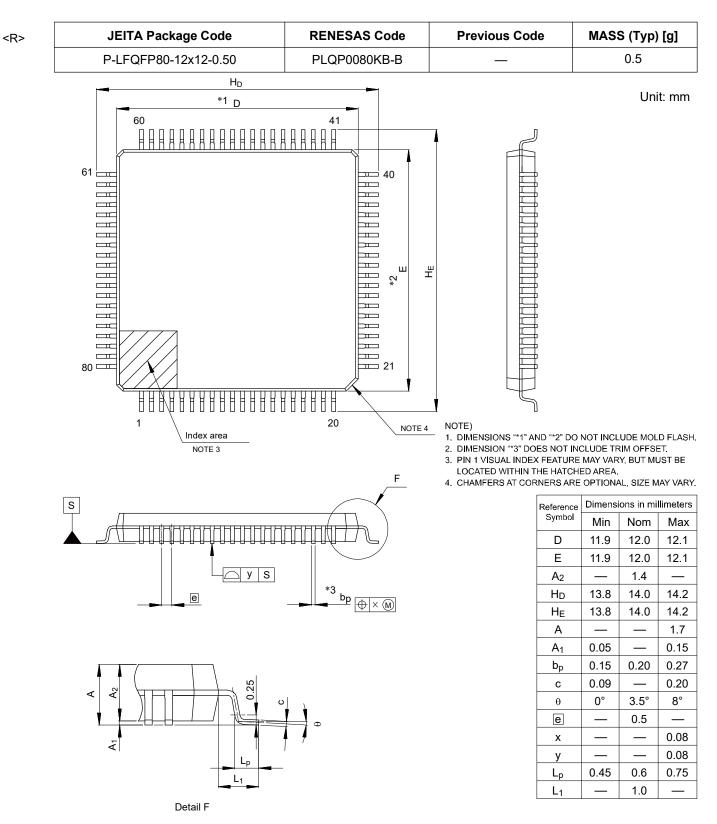


Reference	Dimension in Millimeters			
Symbol	Min.	Nom.	Max.	
A	-	-	1.60	
A ₁	0.05	-	0.15	
A ₂	1.35	1.40	1.45	
D	_	12.00	-	
D ₁	_	10.00	-	
E	_	12.00	-	
E1	-	10.00	-	
N	_	64	_	
е	_	0.50	_	
b	0.17	0.22	0.27	
с	0.09	—	0.20	
θ	0°	3.5°	7°	
L	0.45	0.60	0.75	
L	_	1.00	-	
aaa	-	-	0.20	
bbb	-	-	0.20	
ссс	_	_	0.08	
ddd	-	-	0.08	



3.2 80-pin Products

R5F10NMEDFB, R5F10NMGDFB, R5F10NMJDFB

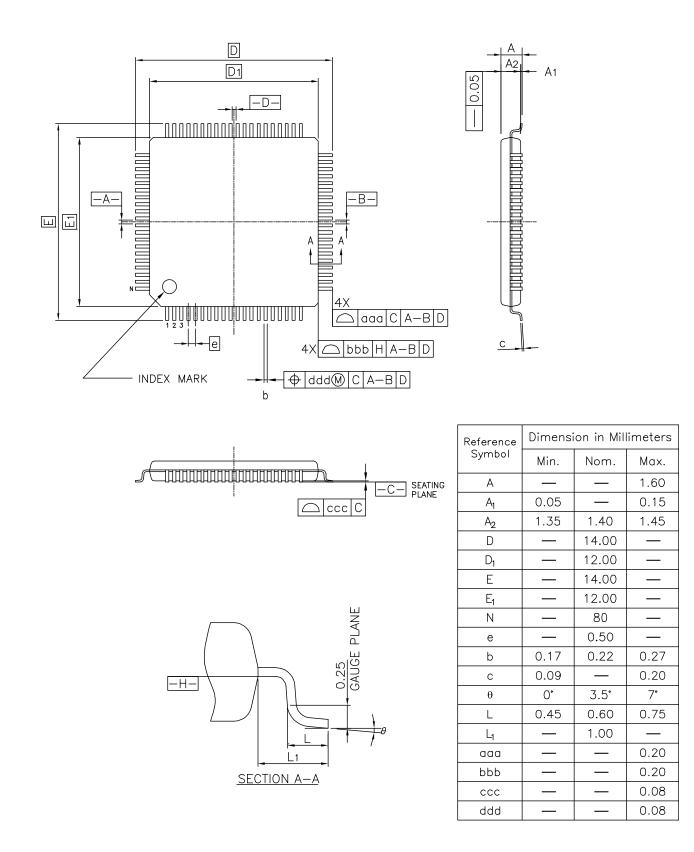


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<R>

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP80-12x12-0.50	PLQP0080KJ-A	0.49

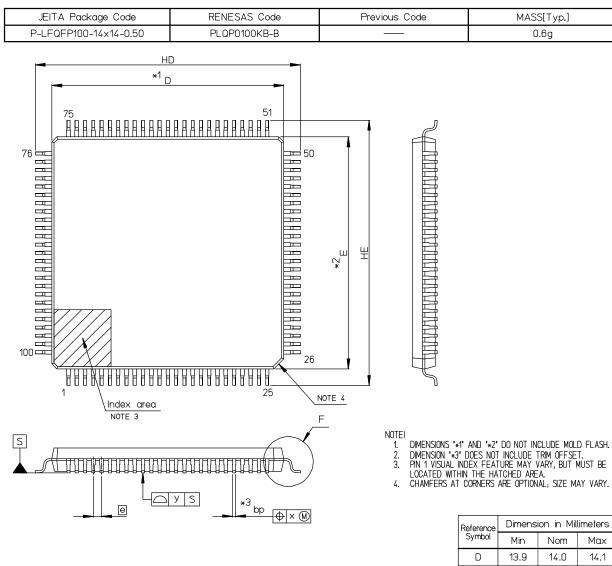


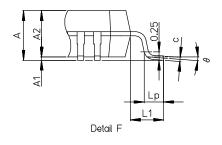


3.3 100-pin Products







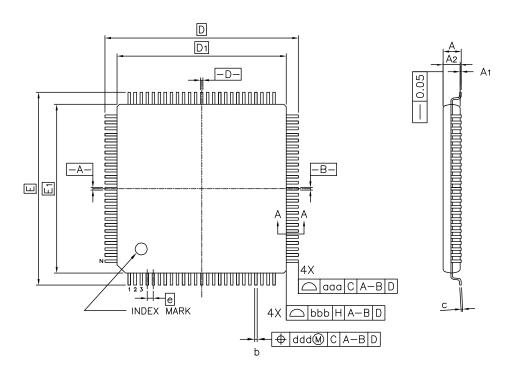


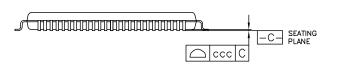
Reference	Dimension in Millimeters		
Symbol	Min	Nom	Max
D	13.9	14.0	14.1
E	13.9	14.0	14.1
A2		1.4	
HD	15.8	16.0	16.2
HE	15.8	16.0	16.2
Α			1.7
A1	0.05		0.15
bp 0.15		0.20	0.27
c 0.09			0.20
θ	θ Ο "		8 "
e		0.5	
×			0.08
У			0.08
Lp	Lp 0.45		0.75
L1		1.0	



<R>

JEITA Package code	RENESAS code	MASS(TYP.)[g]
P-LFQFP100-14x14-0.50	PLQP0100KP-A	0.67





Reference	Dimension in Millimeters			
Symbol	Min.	Nom.	Max.	
Α	_	_	1.60	
A ₁	0.05	-	0.15	
A ₂	1.35	1.40	1.45	
D	—	16.00	—	
D ₁	_	14.00	_	
E	_	16.00	—	
Eı	—	14.00	—	
N	—	100	-	
е	—	0.50	—	
b	0.17	0.22	0.27	
с	0.09	_	0.20	
θ	0°	3.5°	7°	
L	0.45	0.60	0.75	
Ц	—	1.00	—	
aaa	_	-	0.20	
bbb	_	_	0.20	
ccc	_	_	0.08	
ddd	-	-	0.08	



Revision History

RL78/I1C Datasheet

			Description	
Rev.	Rev. Date		Summary	
1.00	May 31, 2016	-	First Edition issued	
2.00	Aug 31, 2018	p.12	Modification of table in 1.6 Outline of Functions	
		p.21, 22	Modification of description in 2.3.1 Pin characteristics	
		p.67	Modification of table in 2.6.1 (1) When reference voltage $_{(+)}$ = AV _{REFP} /ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage $_{(-)}$ = AV _{REFM} /ANI1 (ADREFM = 1), target pins: ANI2 to ANI5 and internal reference voltage	
		p.68	Modification of table in 2.6.1 (2) When reference voltage $_{(+)} = V_{DD}$ (ADREFP1 = 0, ADREFP0 = 0), reference voltage $_{(-)} = V_{SS}$ (ADREFM = 0), target pins: ANI0 to ANI5 and internal reference voltage	
		p.69	Modification of parameter and symbol, and addition of note 2 in 2.6.2 (1) Reference voltage	
		p.70	Modification of condition and unit in 2.6.2 (2) Analog input	
		p.72	Modification of typical value in 2.6.2 (4) 2 kHz sampling mode	
2.10	Aug 23, 2019	Throughout	Addition of products in which AES function is not available (R5F11TLG and R5F11TLE)	
		p.1	Addition of description in 1.1 Features	
		p.3	Modification of note 2 in 1.1 Features	
		p.4	Modification of Figure 1-1 Part Number, Memory Size, and Package of RL78/I1C	
		p.4	Modification of Table 1-1 List of Ordering Part Numbers	
		p.12	Deletion of note 1 in the "100-pin" column in 1.6 Outline of Functions	
		p.13, 14	Modification of 1.6 Outline of Functions	
		p.78	Modification of 2.7.3 VBAT pin voltage detection characteristics	
		p.79	Modification of 2.7.4 VRTC pin voltage detection characteristics	
		p.82	Deletion of note 2 for V_{L1} in 2.8.2 Internal voltage boosting method, (1) 1/3 bias method	
		p.83	Deletion of note 2 for V_{L1} in 2.8.2 Internal voltage boosting method, (2) 1/4 bias method	
2.11	Nov 30, 2022	Throughout	The module name for CSI was changed to simplified SPI.	
			"Wait" was modified to "clock stretch"	
		p.4	Modification of Figure 1-1. Part Number, Memory Size, and Package of RL78/I1C	
		p.5	Modification of Table 1-1. List of Ordering Part Numbers	
		p.88	Modification of package drawing in 3.1 64-pin Products (PLQP0064KB-C)	
		p.89	Addition of package drawing in 3.1 64-pin Products (PLQP0064KL-A)	
		p.90	Modification of package drawing in 3.2 80-pin Products (PLQP0080KB-B	
		p.91	Addition of package drawing in 3.2 80-pin Products (PLQP0080KJ-A)	
		p.92	Modification of package drawing in 3.3 100-pin Products (PLQP0100KB-B)	
		p.93	Addition of package drawing in 3.3 100-pin Products (PLQP0100KP-A)	

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The following usage notes are applicable to all Microprocessing unit and Microcontroller unit products from Renesas. For detailed usage notes on the products covered by this document, refer to the relevant sections of the document as well as any technical updates that have been issued for the products.

1. Precaution against Electrostatic Discharge (ESD)

A strong electrical field, when exposed to a CMOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop the generation of static electricity as much as possible, and quickly dissipate it when it occurs. Environmental control must be adequate. When it is dry, a humidifier should be used. This is recommended to avoid using insulators that can easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors must be grounded. The operator must also be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions must be taken for printed circuit boards with mounted semiconductor devices.

2. Processing at power-on

The state of the product is undefined at the time when power is supplied. The states of internal circuits in the LSI are indeterminate and the states of register settings and pins are undefined at the time when power is supplied. In a finished product where the reset signal is applied to the external reset pin, the states of pins are not guaranteed from the time when power is supplied until the reset process is completed. In a similar way, the states of pins in a product that is reset by an on-chip power-on reset function are not guaranteed from the time when power is supplied until the power is supplied until the power reaches the level at which reseting is specified.

3. Input of signal during power-off state

Do not input signals or an I/O pull-up power supply while the device is powered off. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Follow the guideline for input signal during power-off state as described in your product documentation.

4. Handling of unused pins

Handle unused pins in accordance with the directions given under handling of unused pins in the manual. The input pins of CMOS products are generally in the high-impedance state. In operation with an unused pin in the open-circuit state, extra electromagnetic noise is induced in the vicinity of the LSI, an associated shoot-through current flows internally, and malfunctions occur due to the false recognition of the pin state as an input signal become possible.

5. Clock signals

After applying a reset, only release the reset line after the operating clock signal becomes stable. When switching the clock signal during program execution, wait until the target clock signal is stabilized. When the clock signal is generated with an external resonator or from an external oscillator during a reset, ensure that the reset line is only released after full stabilization of the clock signal. Additionally, when switching to a clock signal produced with an external resonator or by an external oscillator while program execution is in progress, wait until the target clock signal is stable.

6. Voltage application waveform at input pin

Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between V_{IL} (Max.) and V_{IH} (Min.) due to noise, for example, the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between V_{IL} (Max.) and V_{IH} (Min.).

7. Prohibition of access to reserved addresses

Access to reserved addresses is prohibited. The reserved addresses are provided for possible future expansion of functions. Do not access these addresses as the correct operation of the LSI is not guaranteed.

8. Differences between products

Before changing from one product to another, for example to a product with a different part number, confirm that the change will not lead to problems. The characteristics of a microprocessing unit or microcontroller unit products in the same group but having a different part number might differ in terms of internal memory capacity, layout pattern, and other factors, which can affect the ranges of electrical characteristics, such as characteristic values, operating margins, immunity to noise, and amount of radiated noise. When changing to a product with a different part number, implement a system-evaluation test for the given product.

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